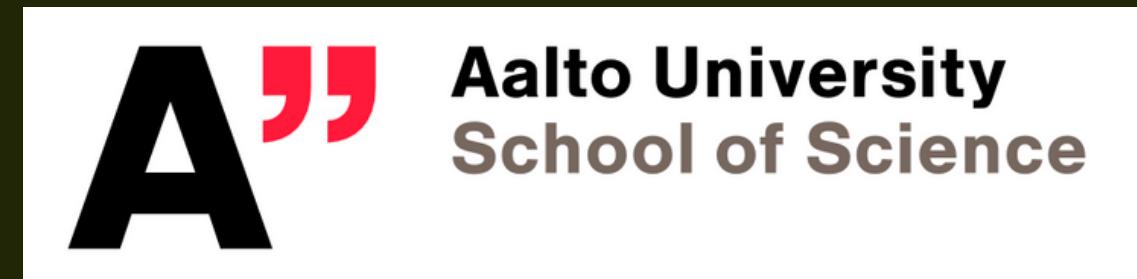


CACTOS

Energy,
but better

21.11.2025
Otaniemi, Espoo



SoC and SoH Estimation of LFP Cells Using Operational Data

Master's Thesis presentation by Olli Ruokojoki



Outline

1. Why Model SoC?
2. Laboratory Testing vs Operational Data
3. Model Architecture: EKF + ECM
4. Model Creation
5. SoC Model Results
6. SoH Estimation
7. SoH Model Results
8. Key Takeaways



Why estimate the State of Charge (SoC)?

- Optimal battery operations
- Bad estimates lead to:
 - → Unexpected SoC behavior
 - → Inefficient operation
 - → Decreased revenue
 - → Energy imbalance
- **Can't be measured directly**
 - Inferred from: U, I, T





CACTOS

TRADITIONAL APPROACH

Model Creation: The Standard Way

- Precise measurement equipment
- Controlled temperature chambers
- Weeks or months of testing
- Highly controlled environments
- **Not representative of real use**





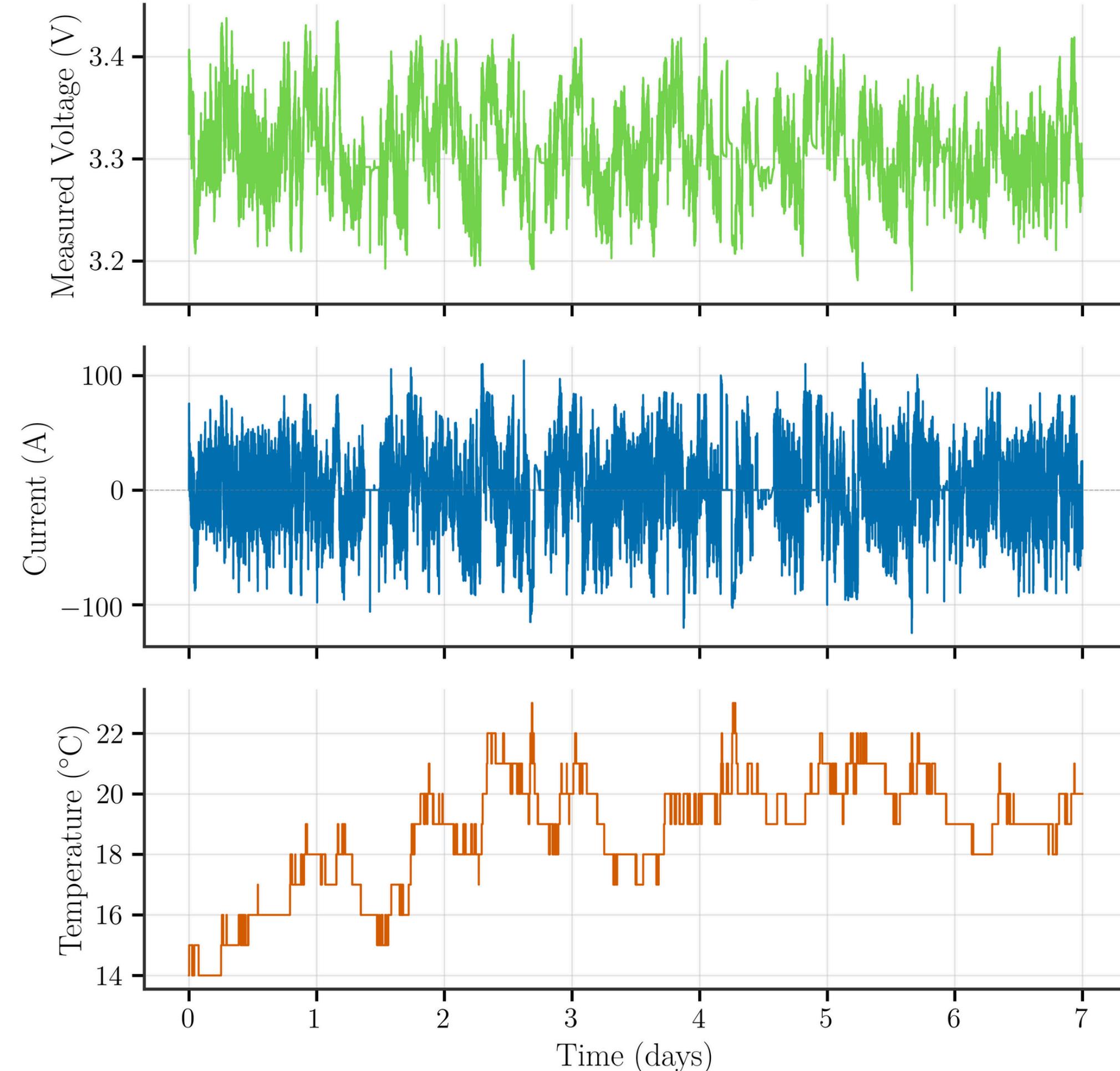
CACTOS

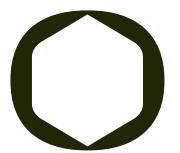
THE DATA-DRIVEN
APPROACH

What If We Used Operational Data Instead?

- **Actually fit for application**
- No extra equipment
- **Difficult**
 - Chaotic and messy
 - No controlled test sequences
 - No ground truth
 - Novelty

Operational Data - 7 Day Period



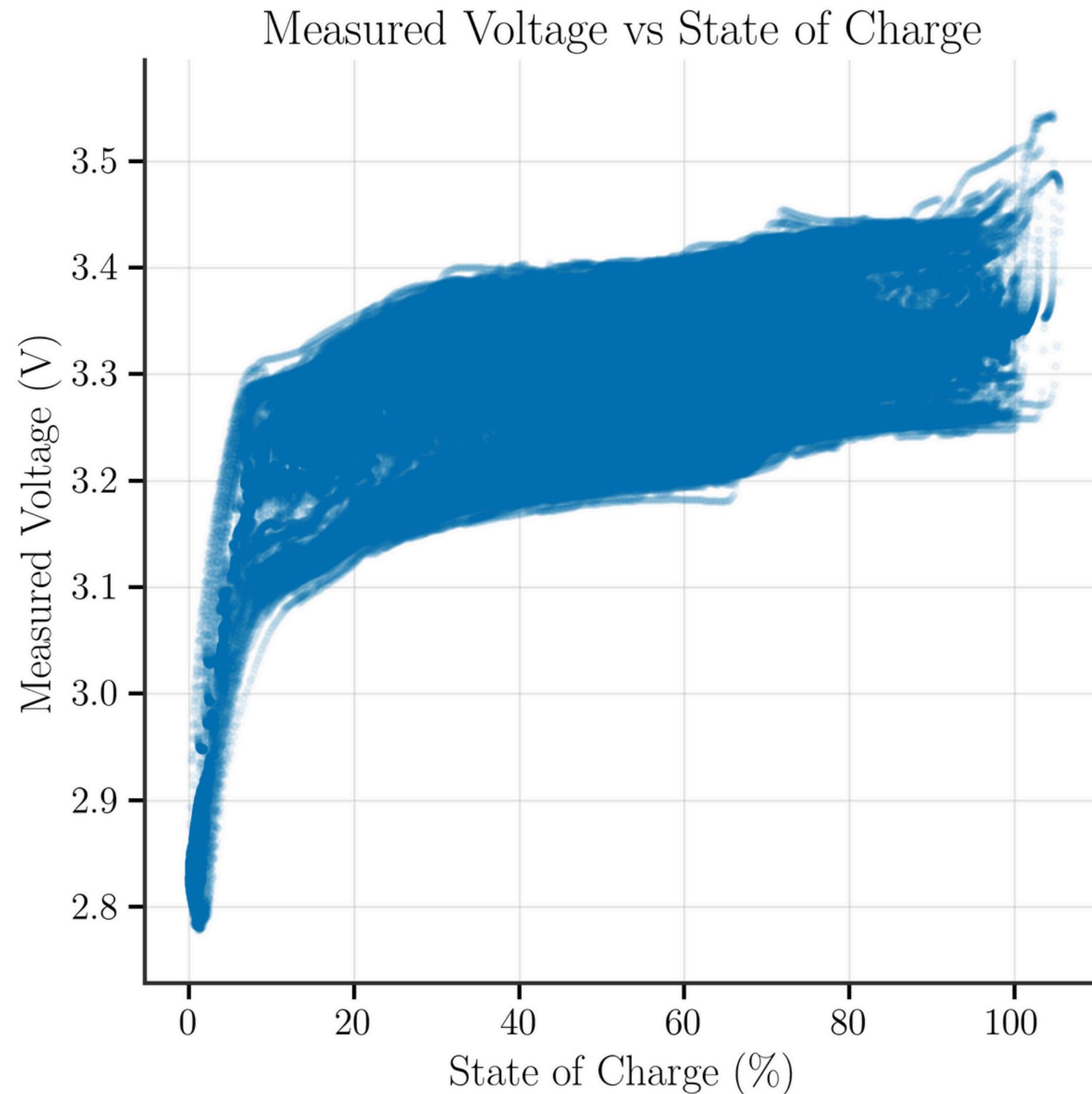


How does an SoC Model work?

1. Current integration (*drift*)
2. Voltage measurements (*noise*)

Sensor fusion:

- **Extended Kalman Filter
(balance)**



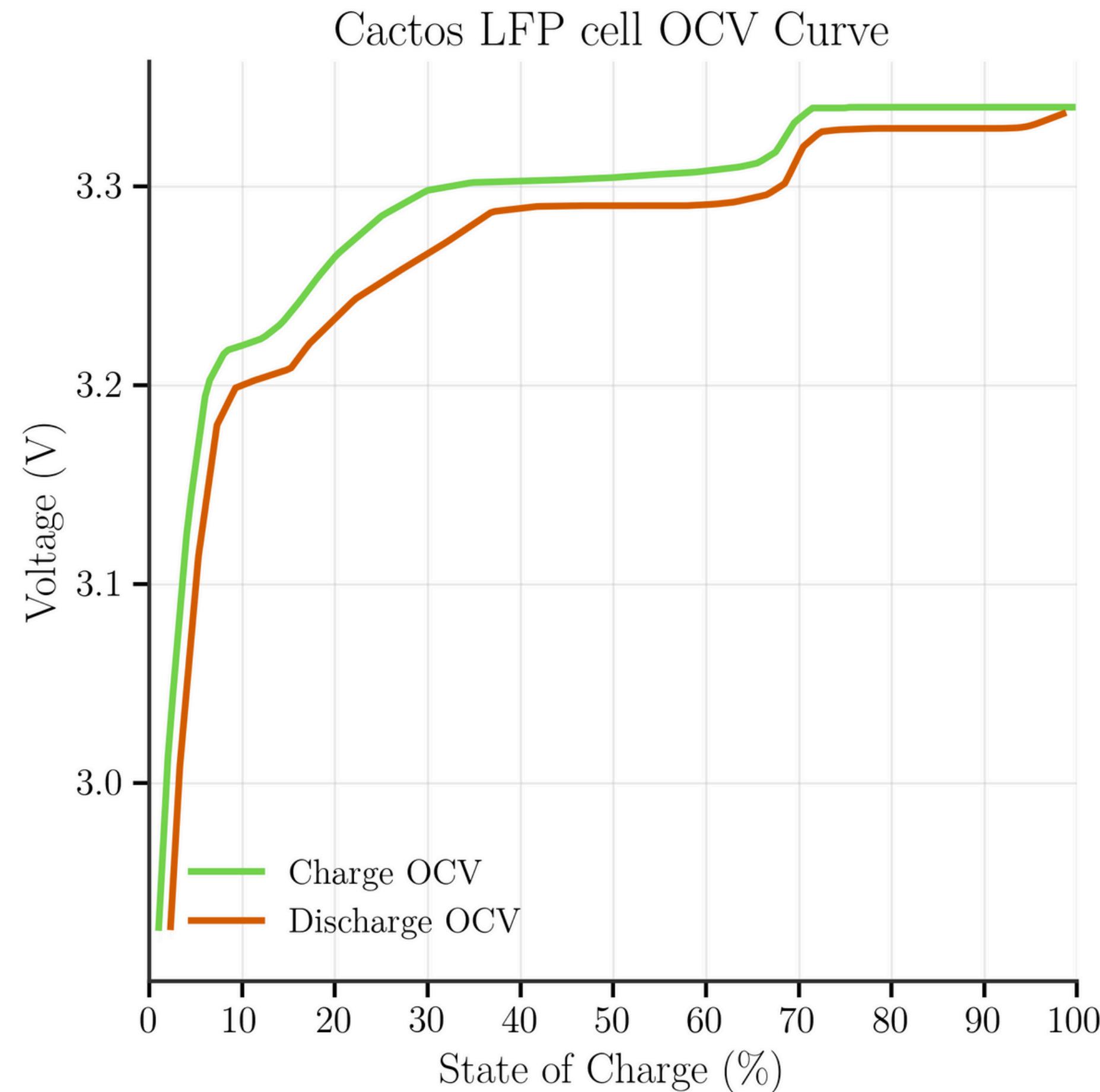


CACTOS

EKF

The Extended Kalman Filter (EKF)

- 1. Prediction: Process model**
 - Current integration
- 2. Update: Measurement model**
 - Voltage → SoC
 - **Requires** a battery model
- 3. Correction**

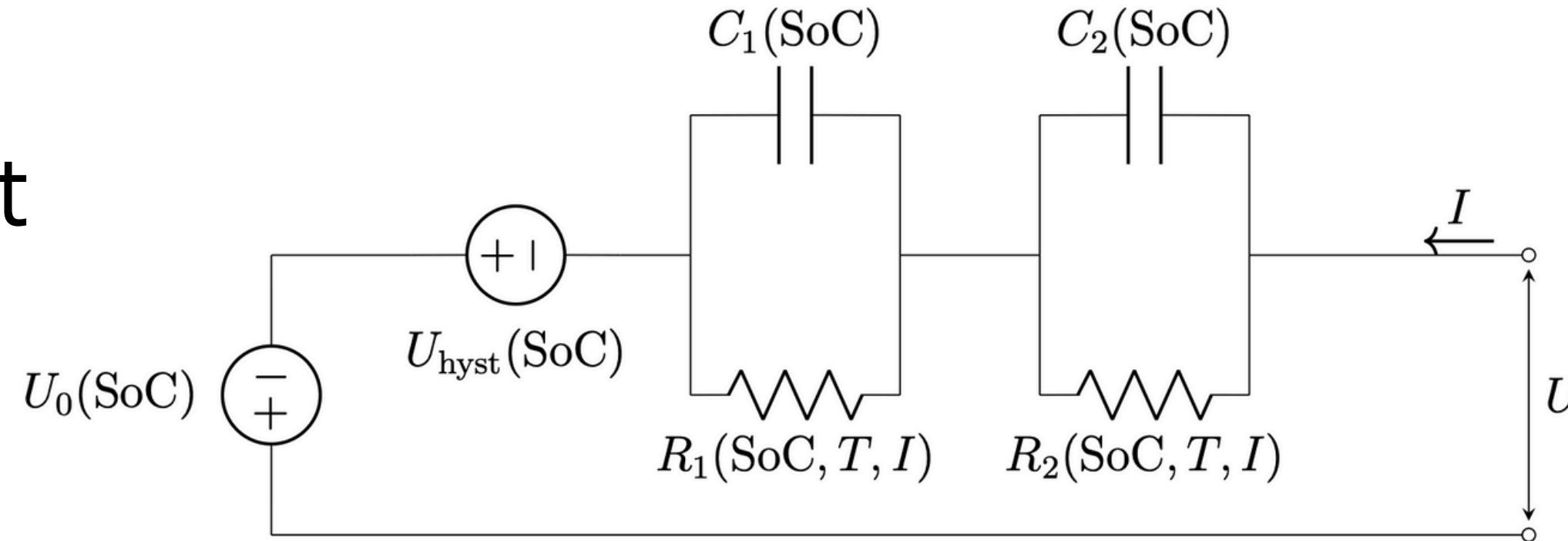




CACTOS

ECM

The Equivalent Circuit Model (ECM)



ECM parameter dependencies

	SoC	Temperature T	Current rate $ I $	Current sign	SoH / aging
U_0	x	[88]			[50, 89]
R_0	[55, 70, 88, 90, 91]	[70, 90–92]	[91, 92]	[39, 70, 91, 93]	[50, 53, 55]
R_1	[50, 55, 70, 88, 90, 91]	[50, 70, 90–92]	[91, 92]	[70, 91, 93]	[53, 55, 88, 94]
C_1	[88, 90, 91]	[90–92]	[91, 92]	[91]	[94]
R_2	[50, 55, 70, 88, 90, 91]	[50, 70, 90–92]	[91, 92]	[70, 91, 93]	[53, 55, 94]
C_2	[88, 90, 91]	[90–92]		[91]	[94]
U_{hyst}	x	[39, 70, 81, 90]			[81, 95, 96]

Table 1 of the Master's Thesis

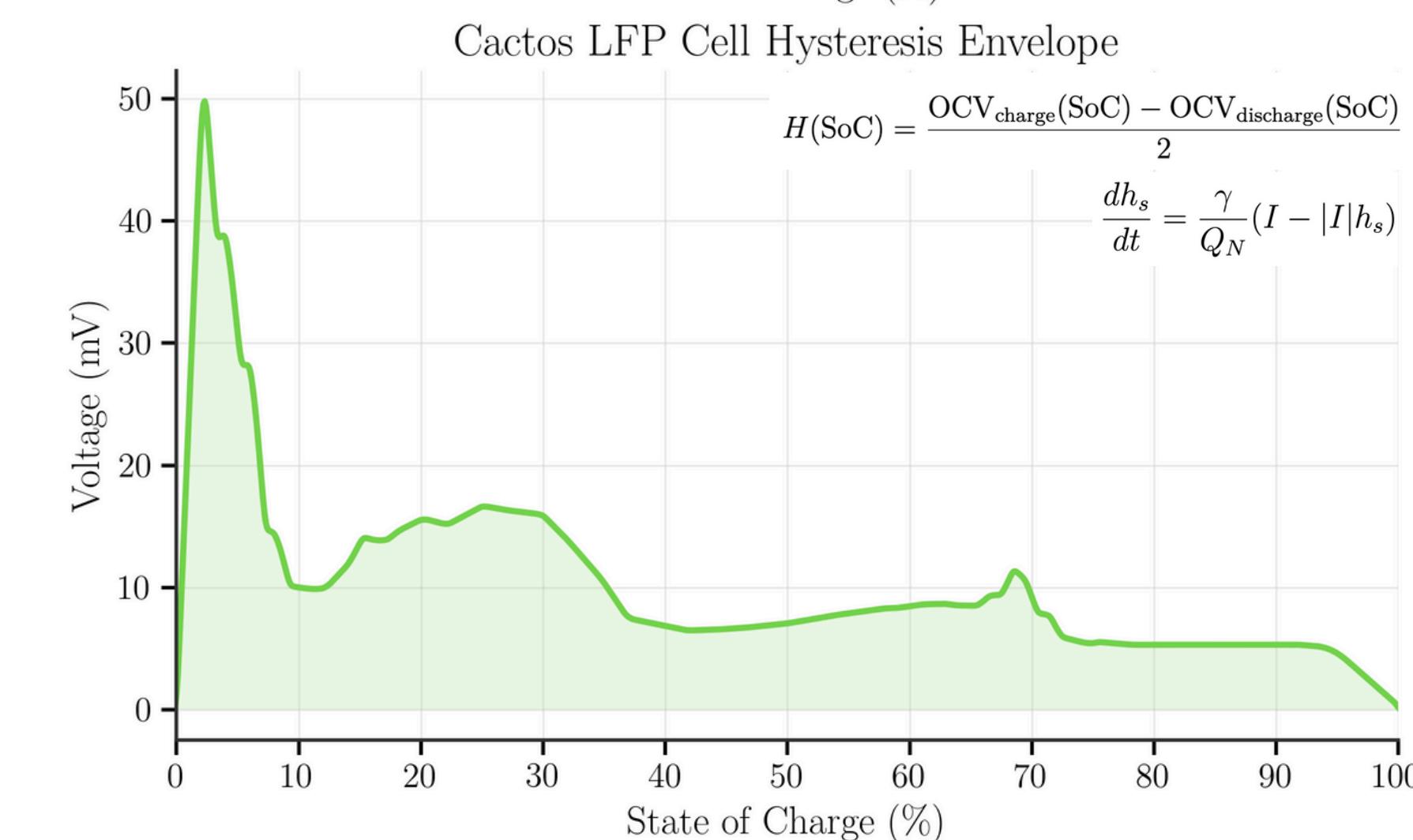
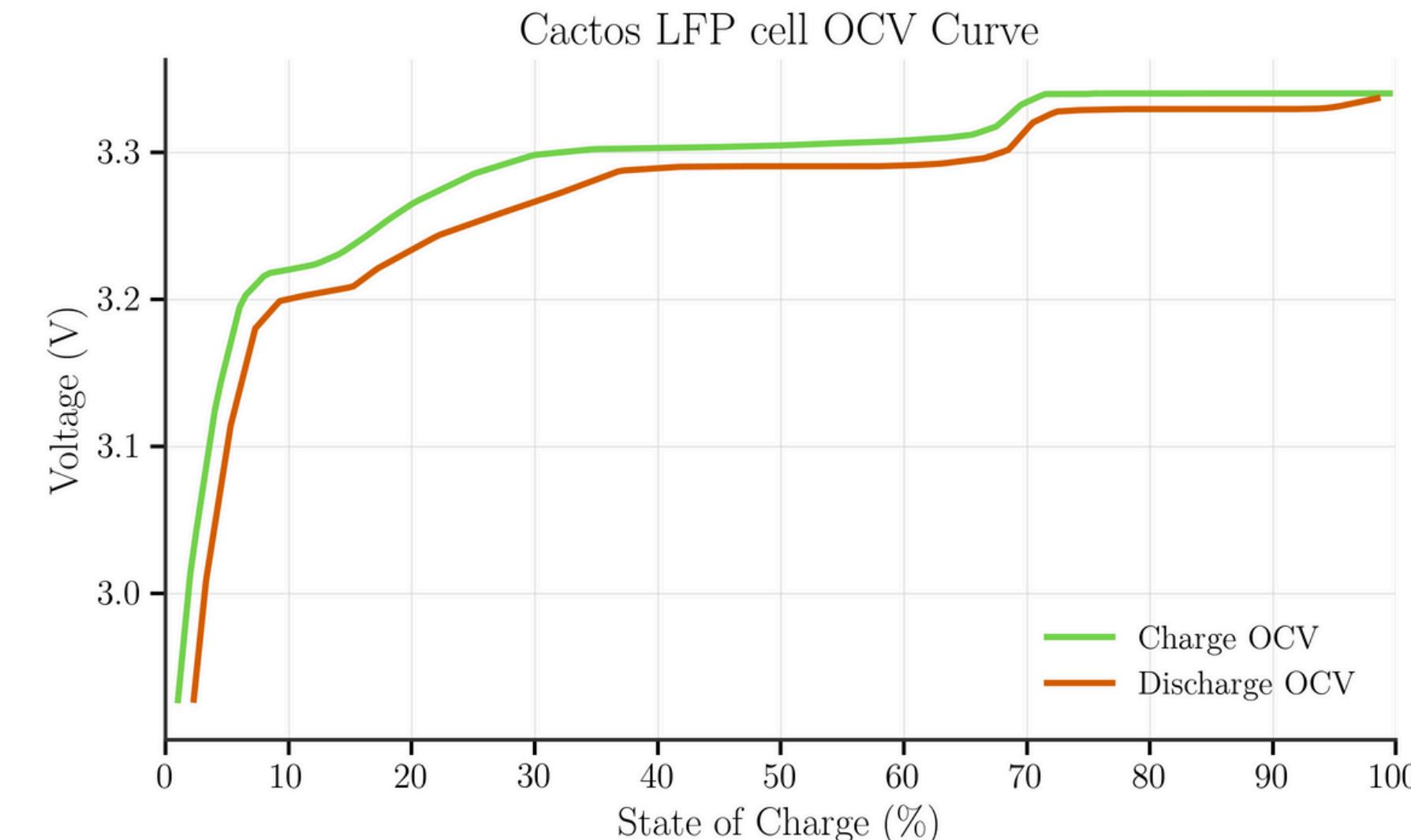
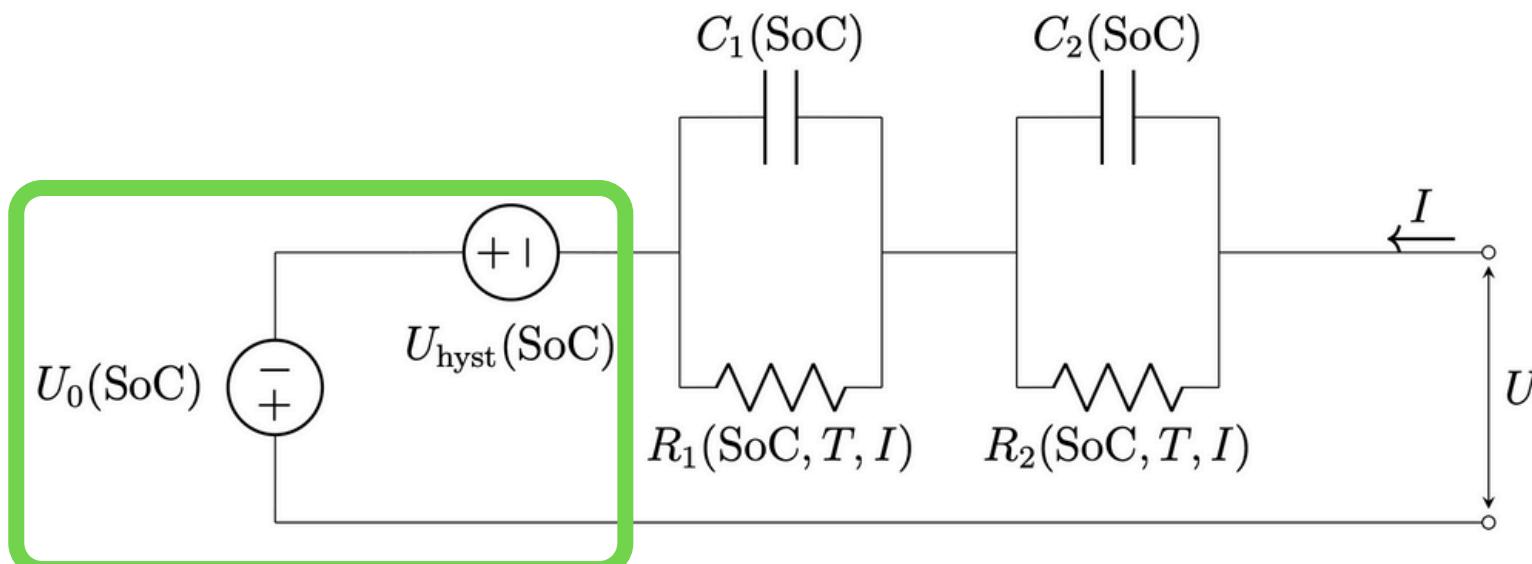


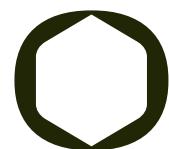
CACTOS

OCV CURVE

The Open-Circuit Voltage (OCV) curve

- The “rest” voltage
- **Maps OCV to SoC**
- Most important component of the ECM
- **Tested** with a 0–100–0% SoC run

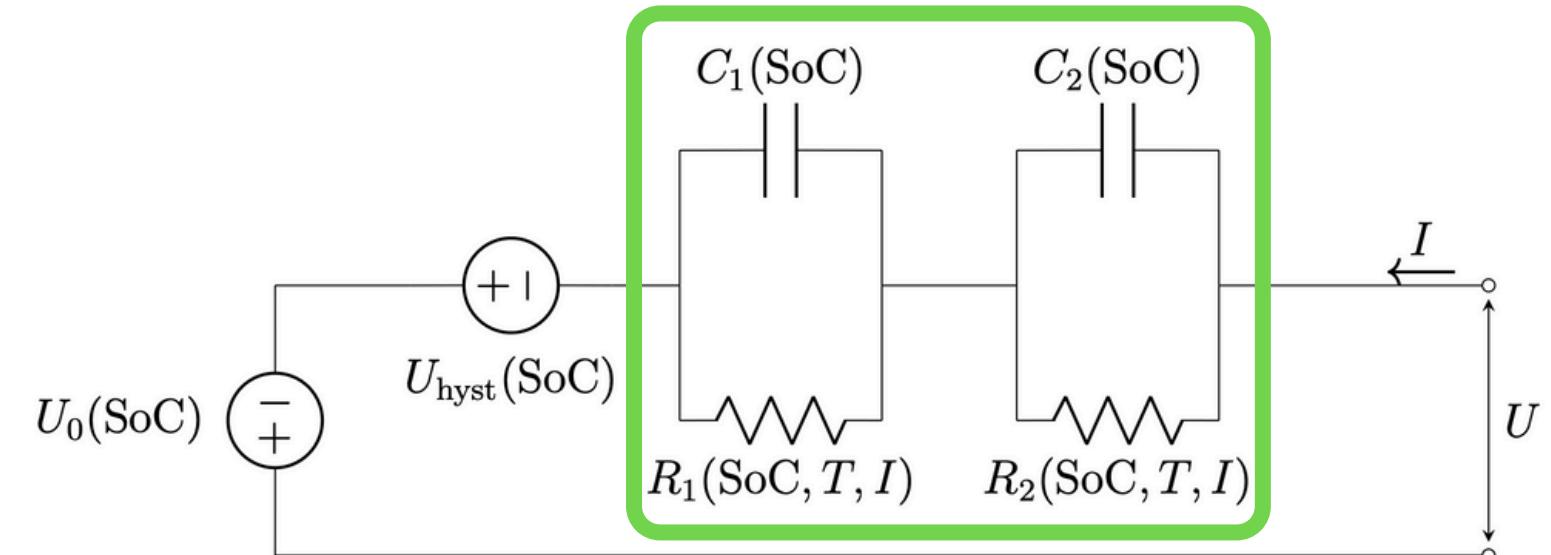




CACTOS

MODEL CREATION
OVERVIEW

Iterative Model Creation



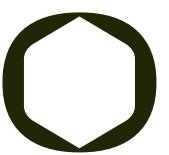
START: INITIAL SOC ESTIMATES

PRE-PROCESSING: TEST SECTIONS

FIT 1: TIME-DEPENDENT PARAMETERS

**FIT RESIDUAL:
RESISTANCE SOC
DEPENDENCY**

**FIT 2: RESISTANCE
TEMPERATURE AND
CURRENT
DEPENDENCIES**



CACTOS

FIT 1

$$U_k = \alpha_k U_k^- + (1 - \alpha_k) U_{ss,k}, \quad k \in \{1, 2\}$$

$$\alpha_k = \exp\left(-\frac{\Delta t}{\tau_k}\right)$$

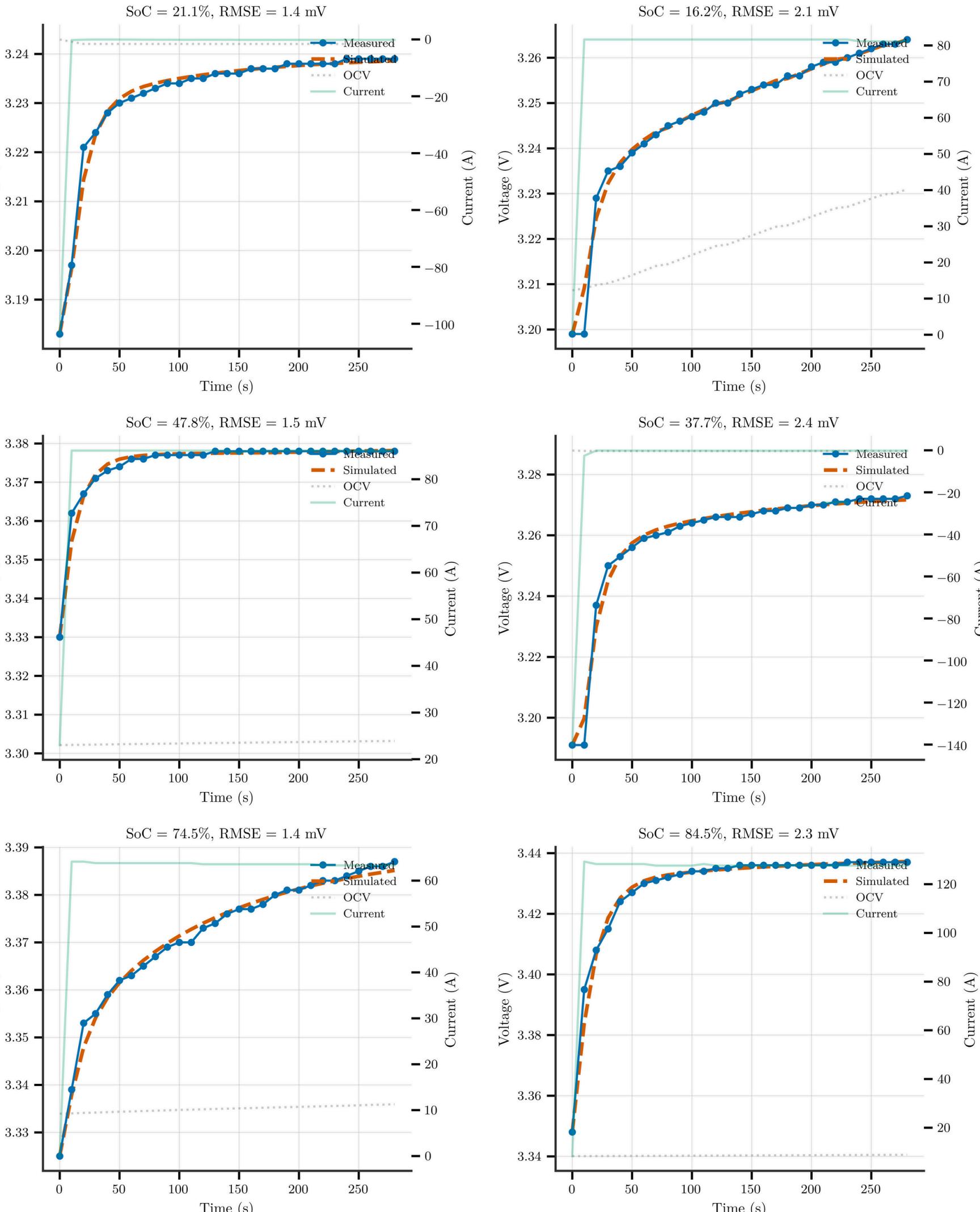
Time dependent parameters

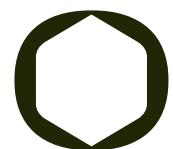
- Assume: exponential decay
- Find: stable current step sections
 - Sharp current change
 - Stable current prior and after
- Fit: time constants and R1/R2
- Resistance values not needed

$$\frac{dU_k}{dt} = -\frac{U_k}{\tau_k} + \frac{R_k}{\tau_k} I(t), \quad k \in \{1, 2\}$$

**PRE-PROCESSING:
TEST SECTIONS**

**FIT 1: TIME-DEPENDENT
PARAMETERS**

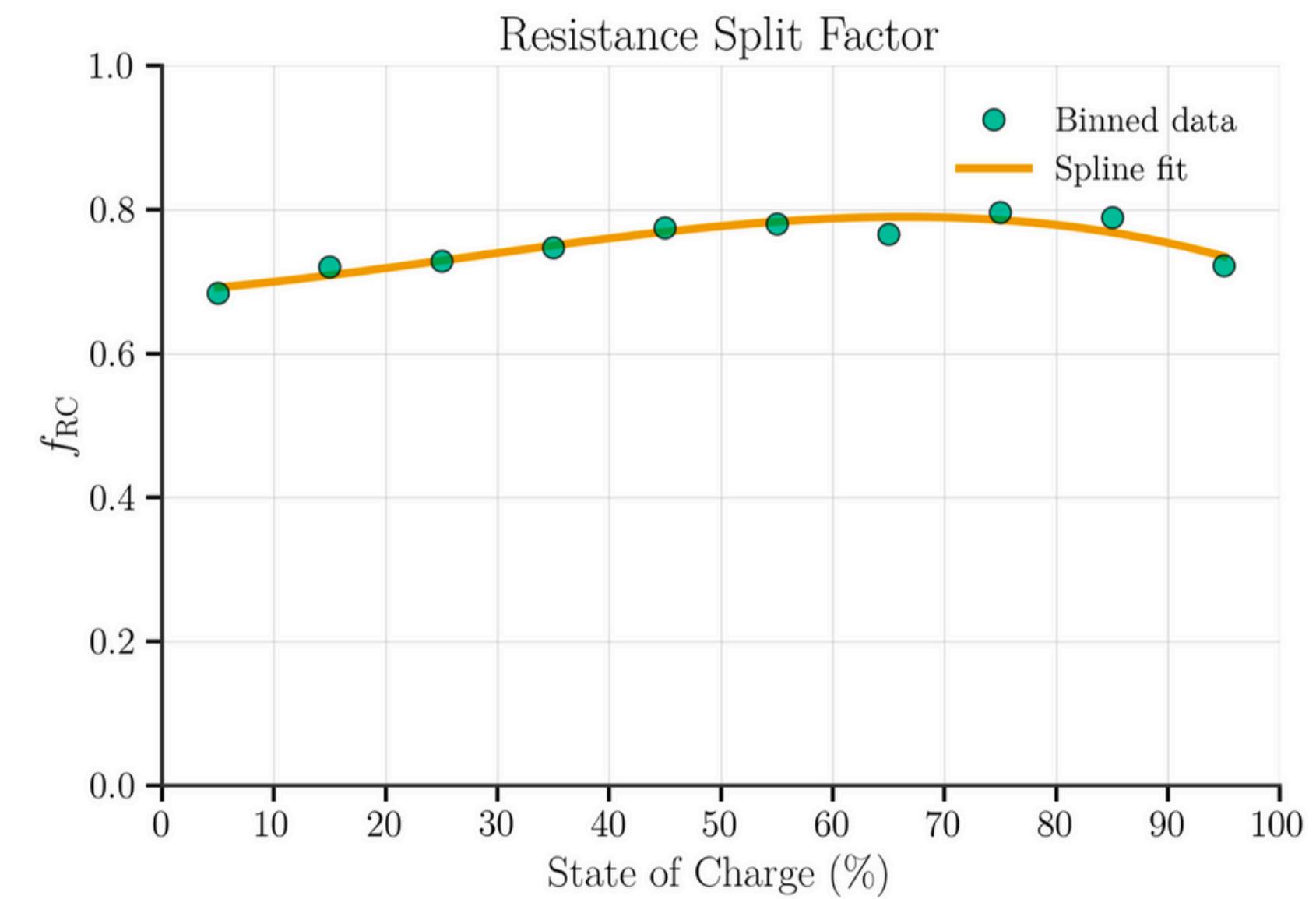
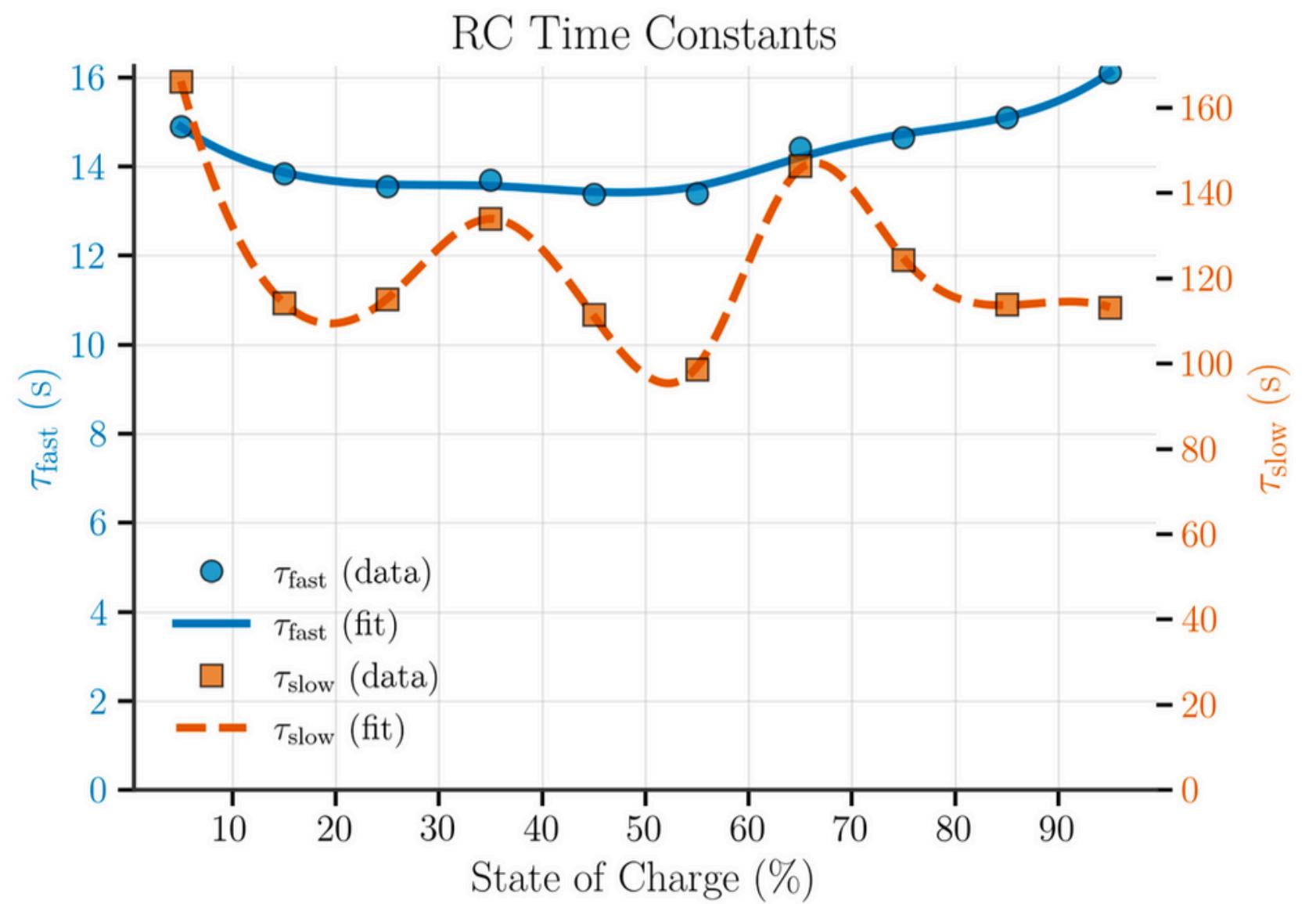




CACTOS

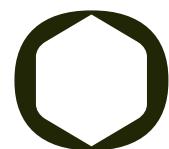
FIT 2

Time dependent parameters



PRE-PROCESSING:
TEST SECTIONS

**FIT 1: TIME-DEPENDENT
PARAMETERS**



CACTOS

FIT 2

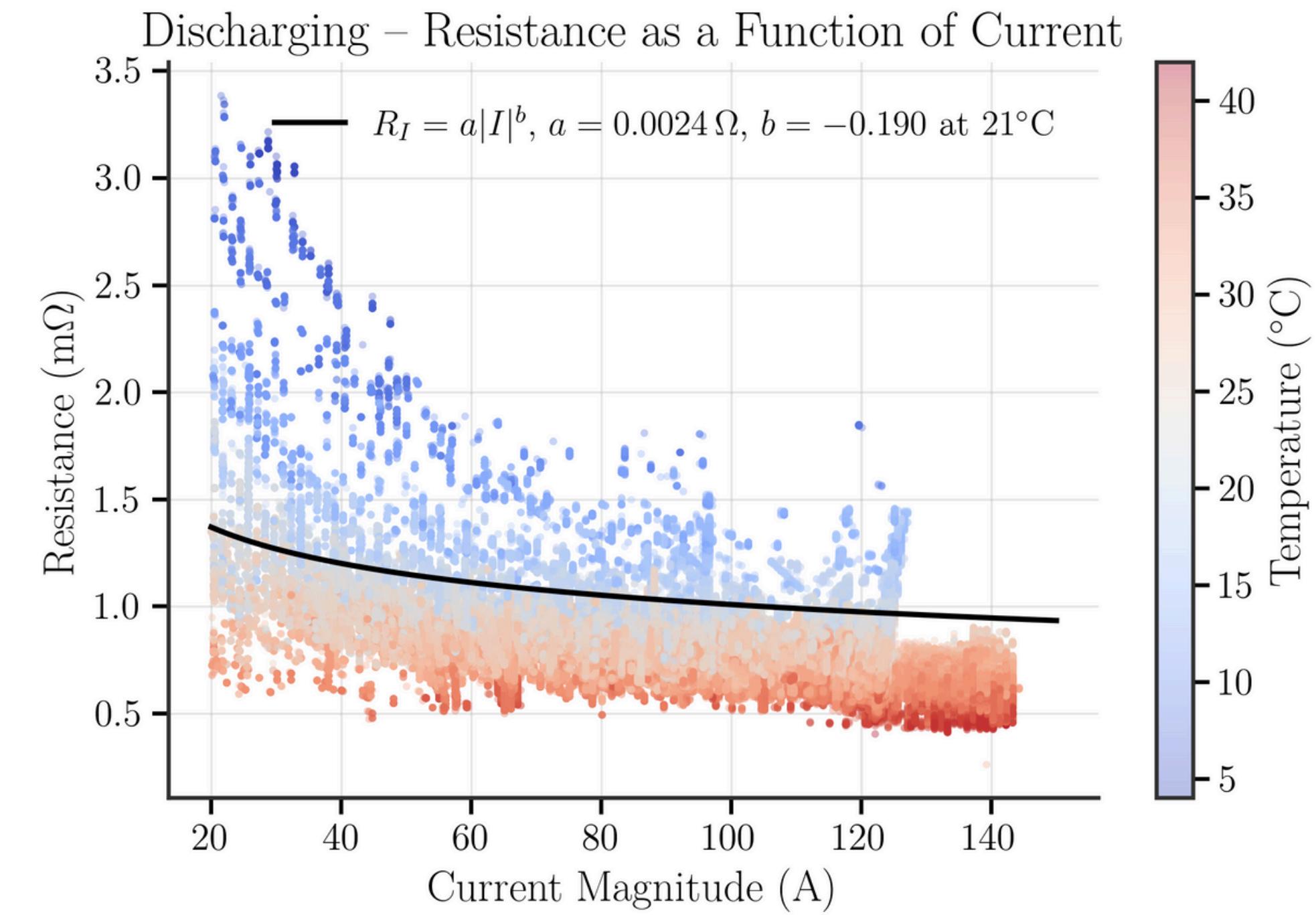
Resistance parameters

- Assume: separable dependencies
- Find: stable sections, all dynamics fully evolved
- Fit:
 - Current and temperature dependency parameters
 - SoC from residual (spline)

FIT 2: RESISTANCE TEMPERATURE AND CURRENT DEPENDENCIES

FIT RESIDUAL: SOC DEPENDENCY

$$R_{\text{tot}}(T, \text{SoC}, I) = R_I(|I|, \sigma) \cdot f_{\text{SoC}}(\text{SoC}, \sigma) \cdot f_T(T, \sigma)$$



$$R_I(|I|, \sigma) = \begin{cases} a_\sigma |I|^{b_\sigma}, & |I| \geq I_0 \\ a_\sigma I_0^{b_\sigma} + a_\sigma b_\sigma I_0^{b_\sigma-1} (|I| - I_0), & |I| < I_0 \end{cases}$$

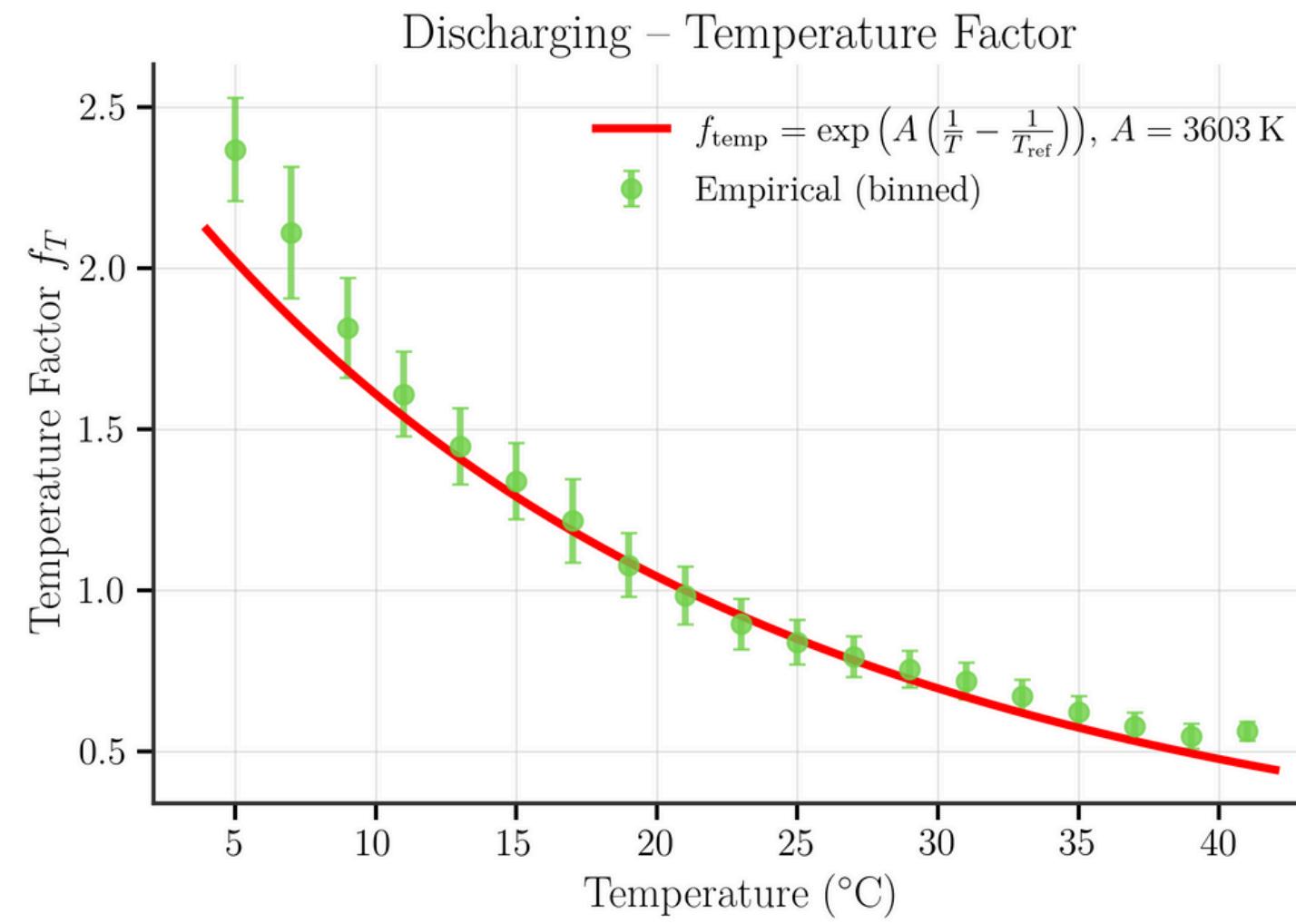


CACTOS

FIT 2

$$R_{\text{tot}}(T, SoC, I) = R_I(|I|, \sigma) \cdot f_{\text{SoC}}(SoC, \sigma) \cdot f_T(T, \sigma)$$

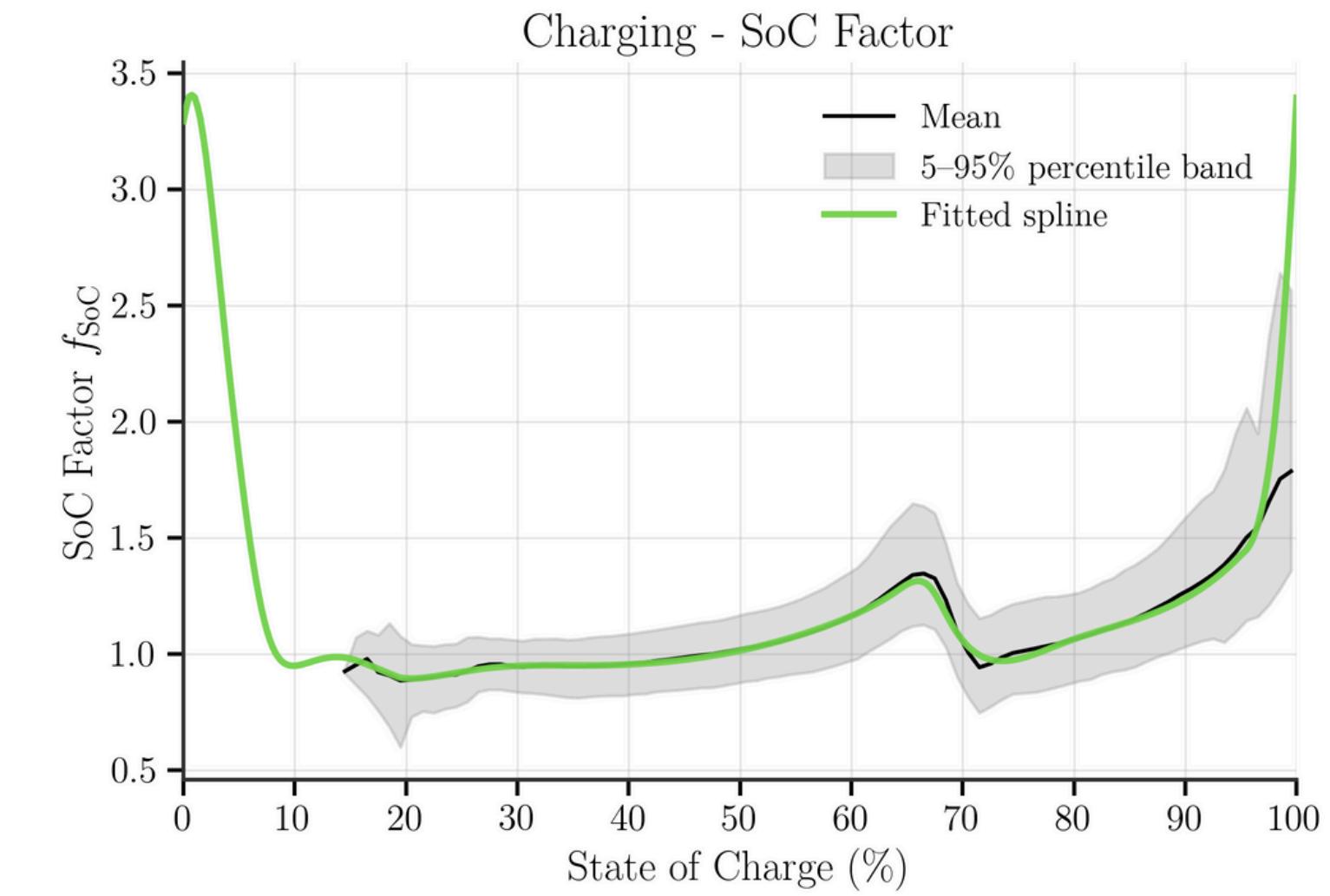
Resistance parameters



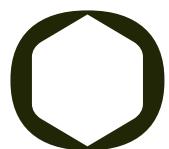
$$f_T(T, \sigma) = \exp\left(A_\sigma\left(\frac{1}{T} - \frac{1}{T_{\text{ref}}}\right)\right)$$

**FIT 2: RESISTANCE
TEMPERATURE AND
CURRENT
DEPENDENCIES**

**FIT RESIDUAL: SOC
DEPENDENCY**

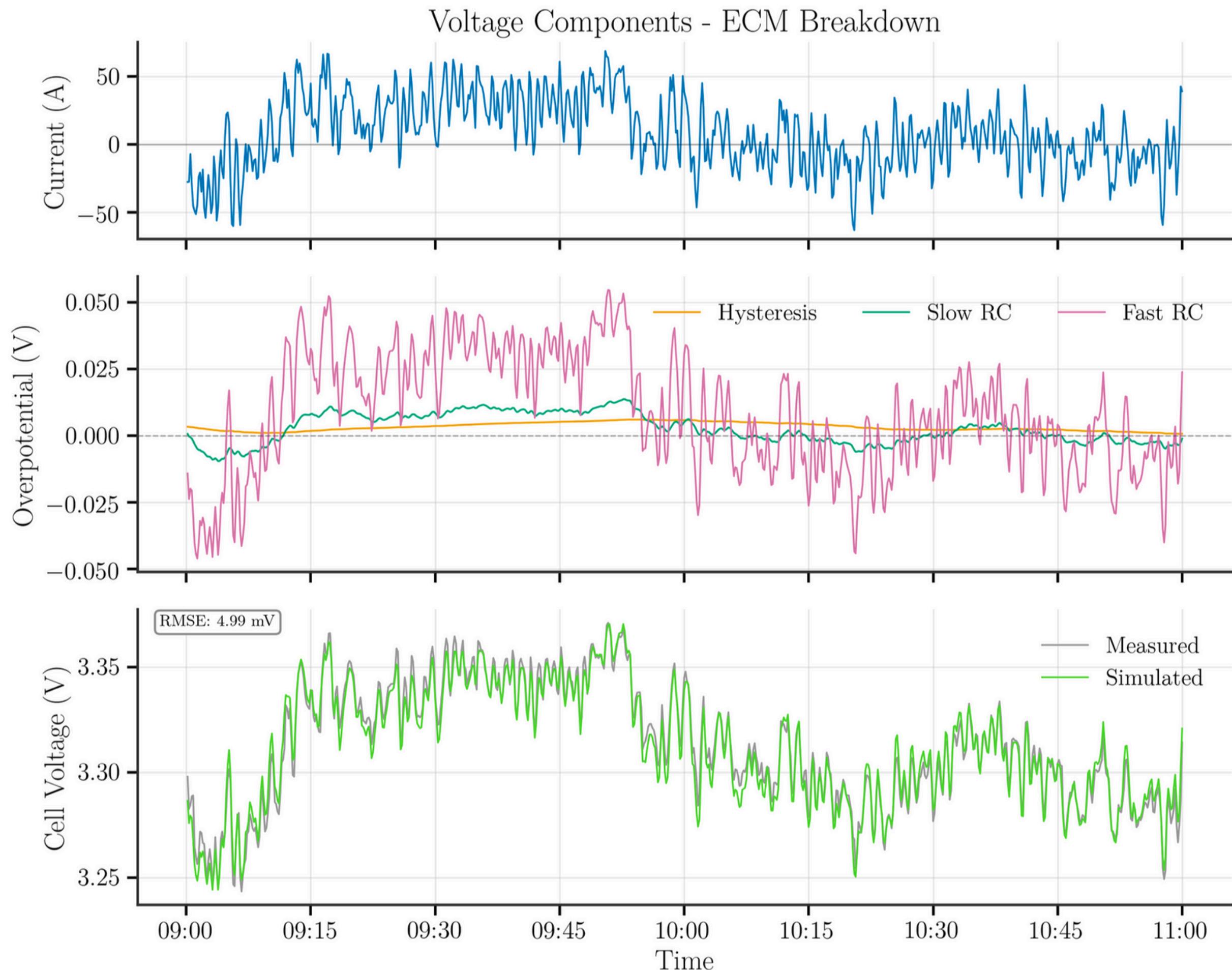


$$f_{\text{SoC}}(\text{SoC}, \sigma) = \frac{R_m}{R_{\text{pred}}(I, T, \sigma)}$$



ECM: Does It Work?

$$U_{\text{sim}} = U_0 + U_{\text{hyst}} + U_1 + U_2$$



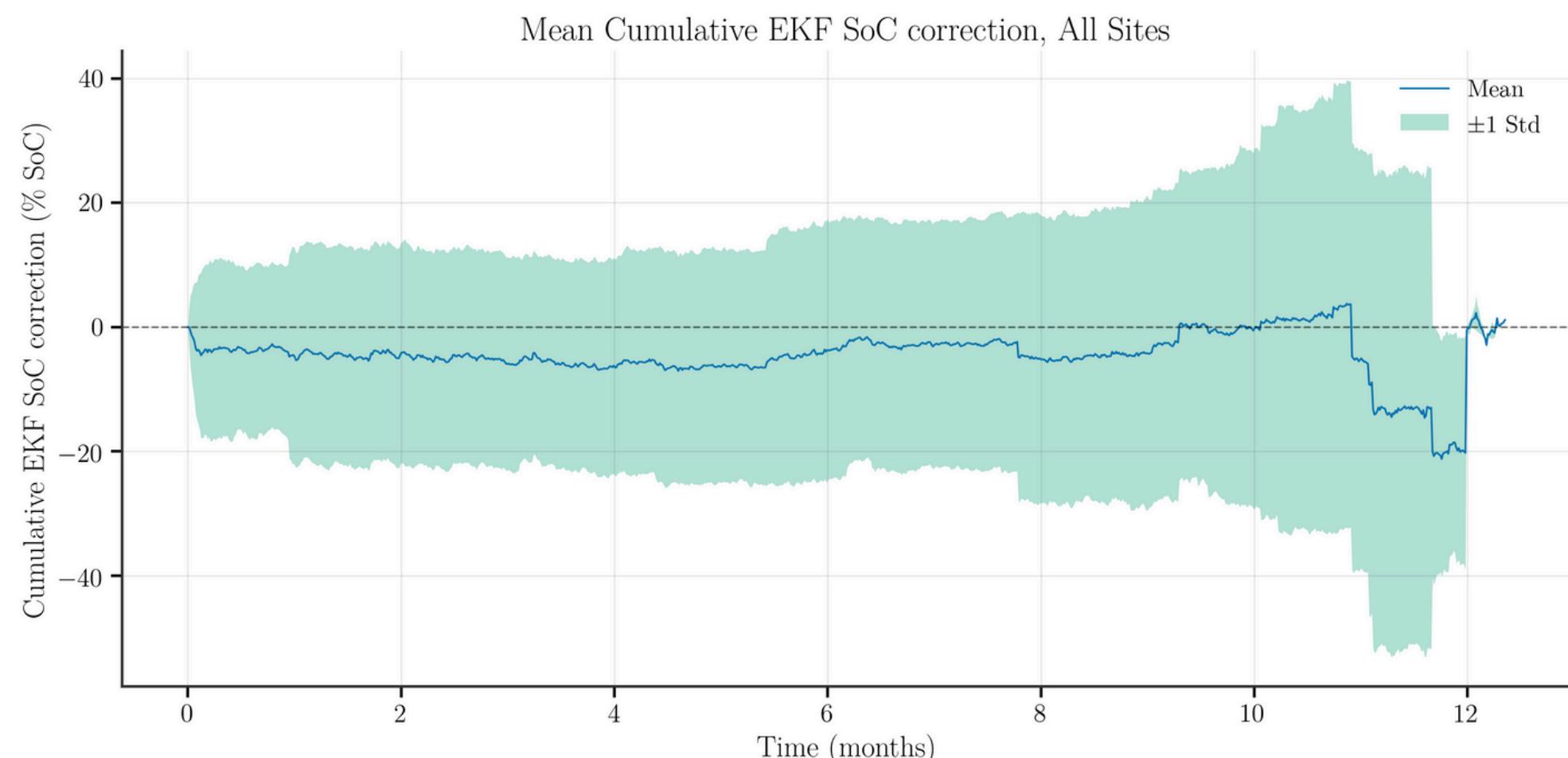
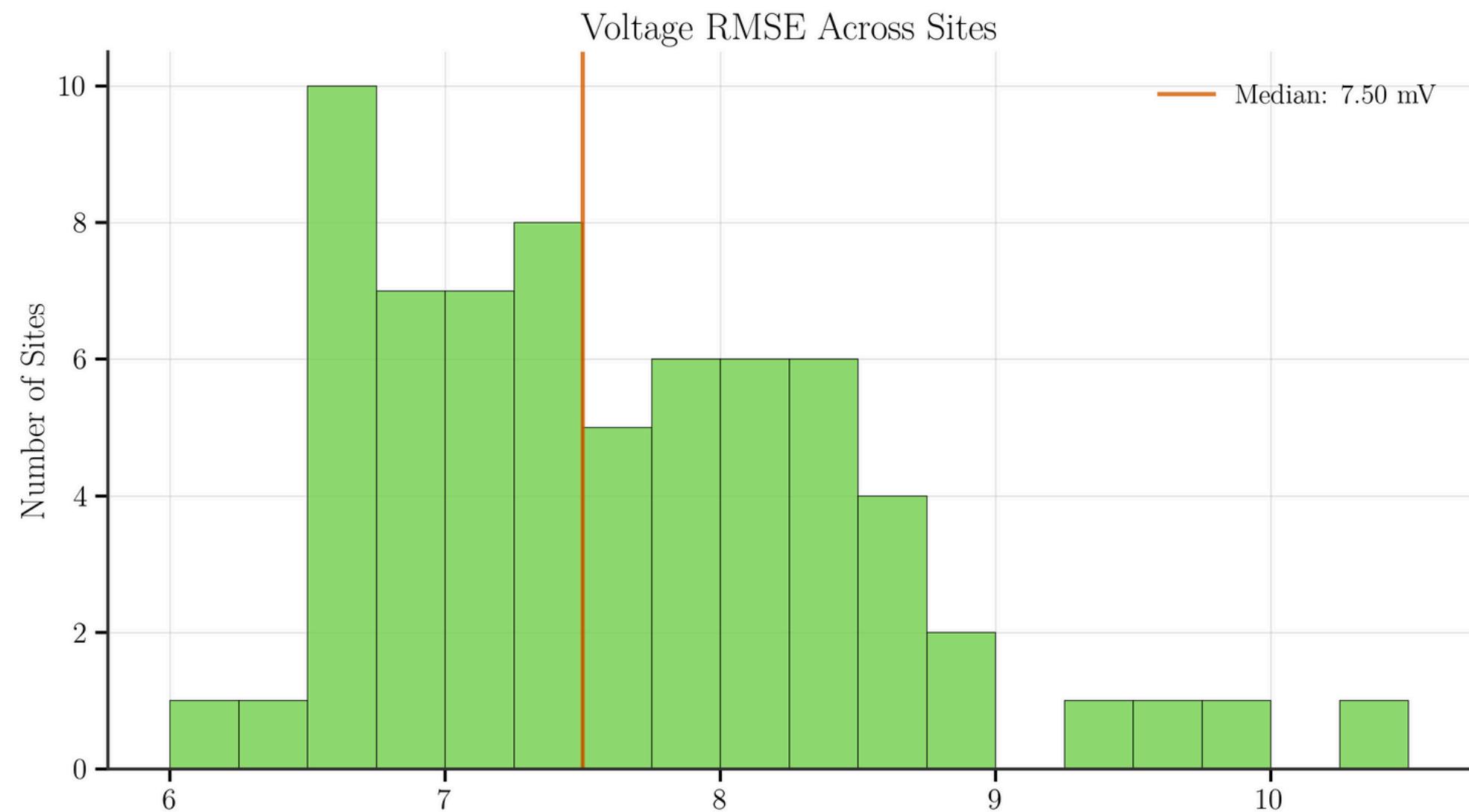
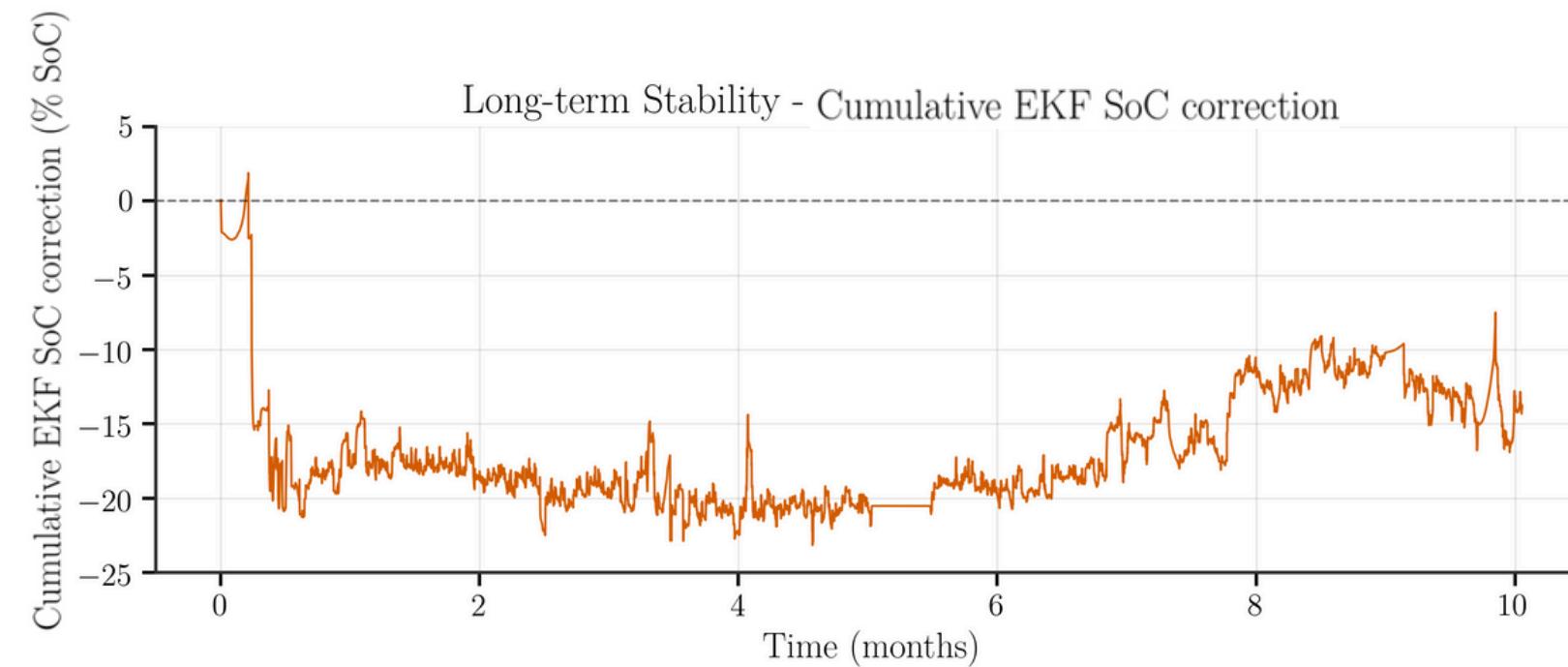


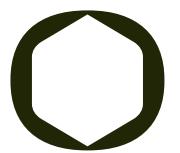
CACTOS

RESULTS: SOC

Results: SoC Model

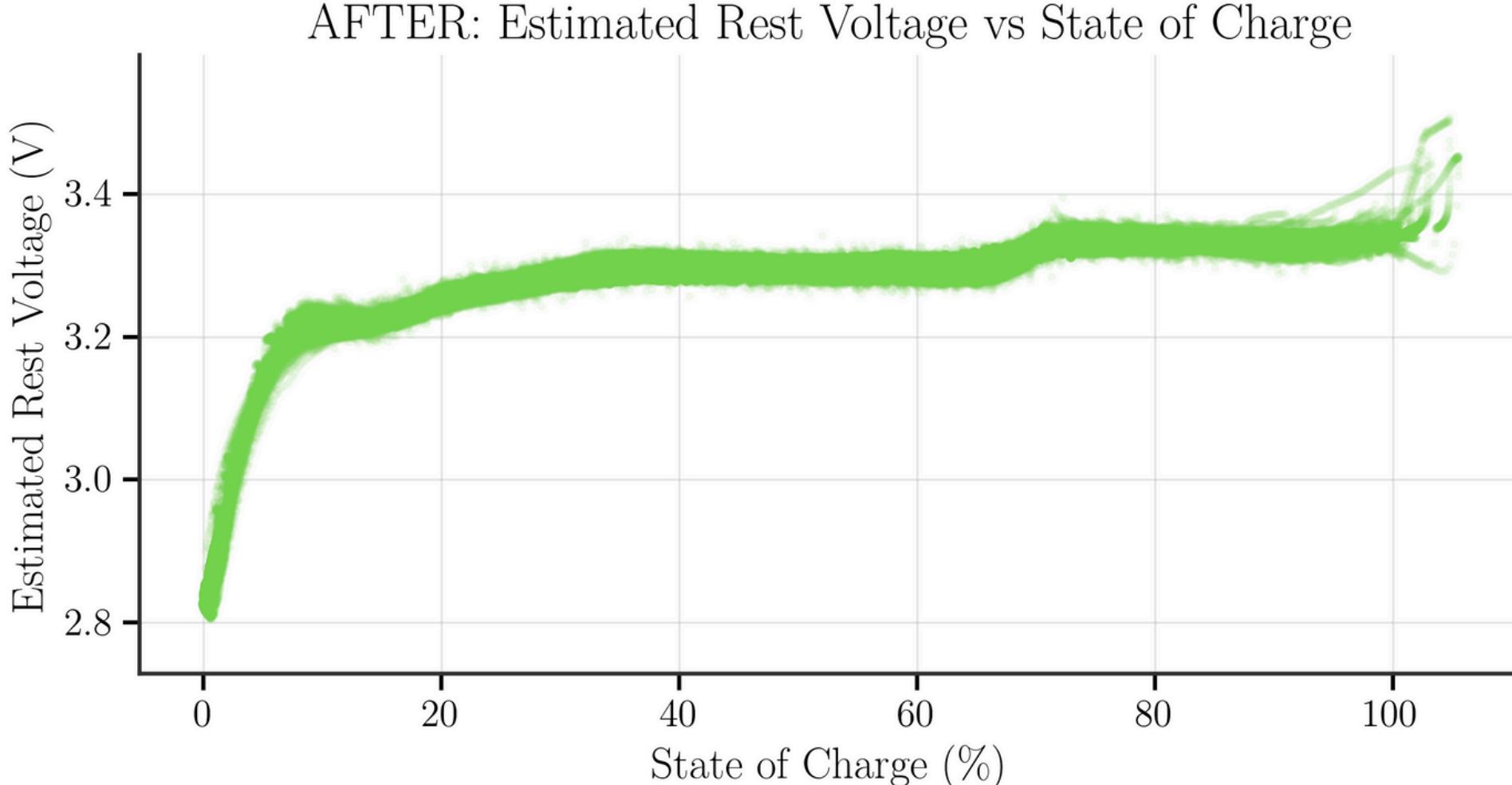
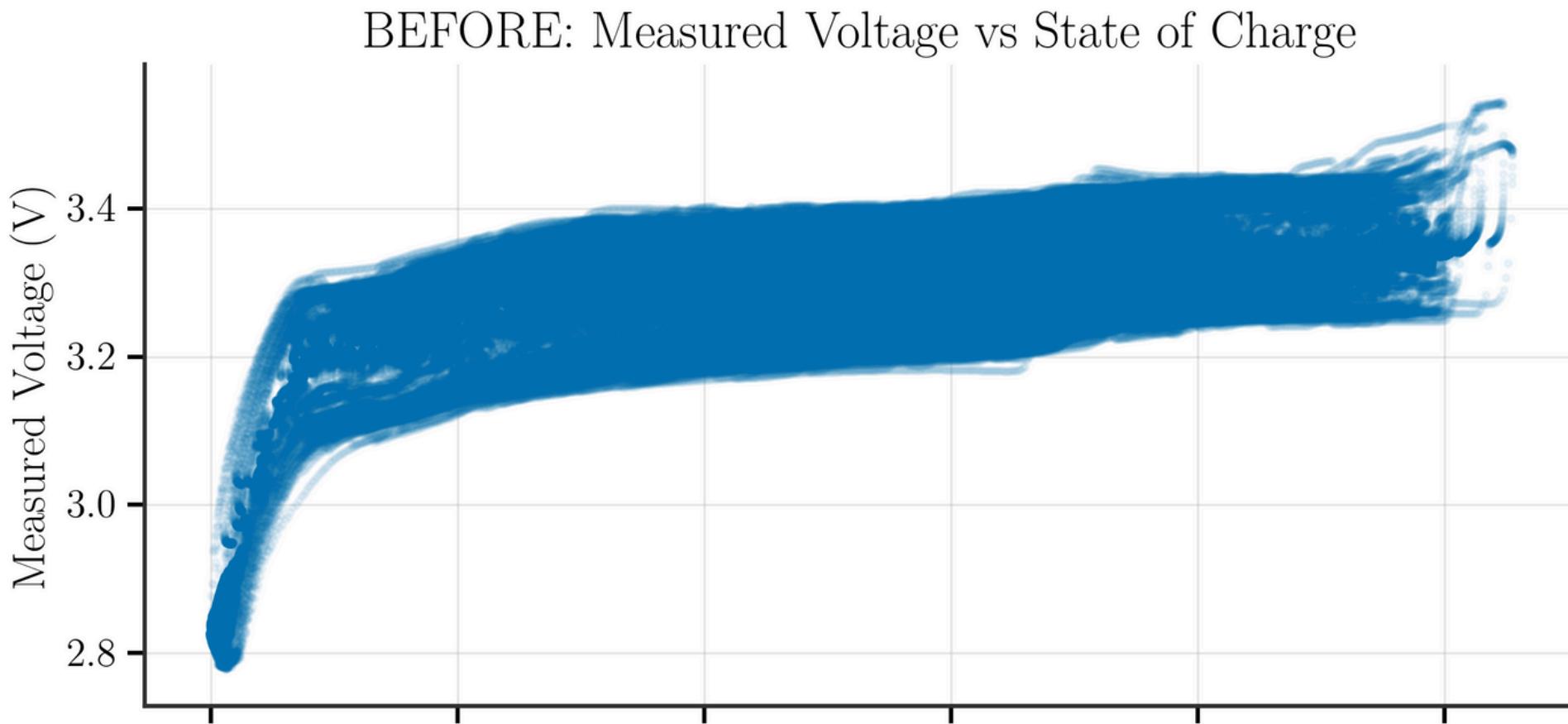
- Across
 - 67 devices
 - 44 years of data
 - 56 GB
- Median voltage **RMSE 7.50 mV**
- Stable SoC corrections
- Literature often reports >10 mV RMSE





Why Does This Matter?

- Fit for our cells in real use
- No lab testing needed
- Adapts to real conditions
- Possibility for improvement through:
 - More data
 - More advanced models



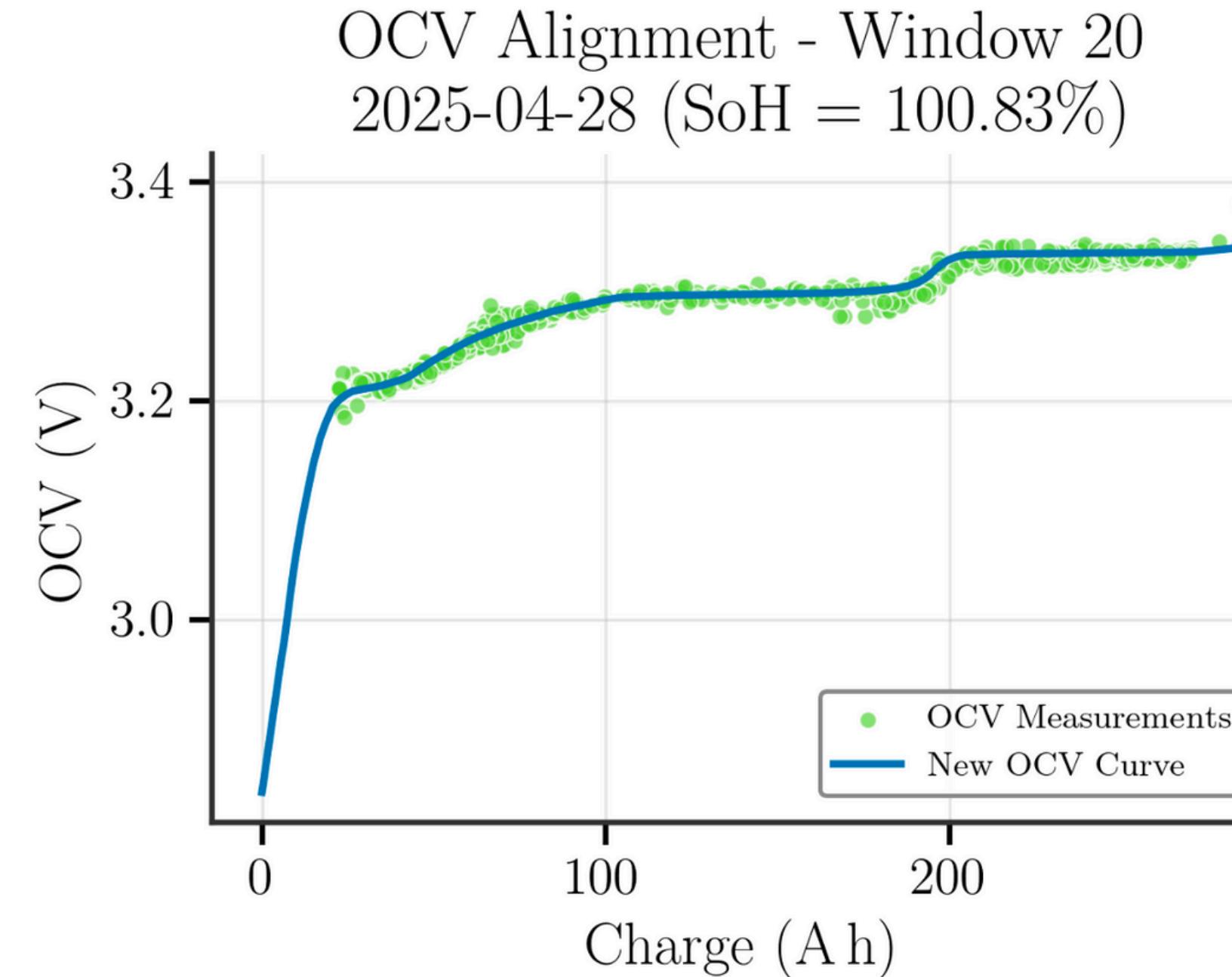


CACTOS

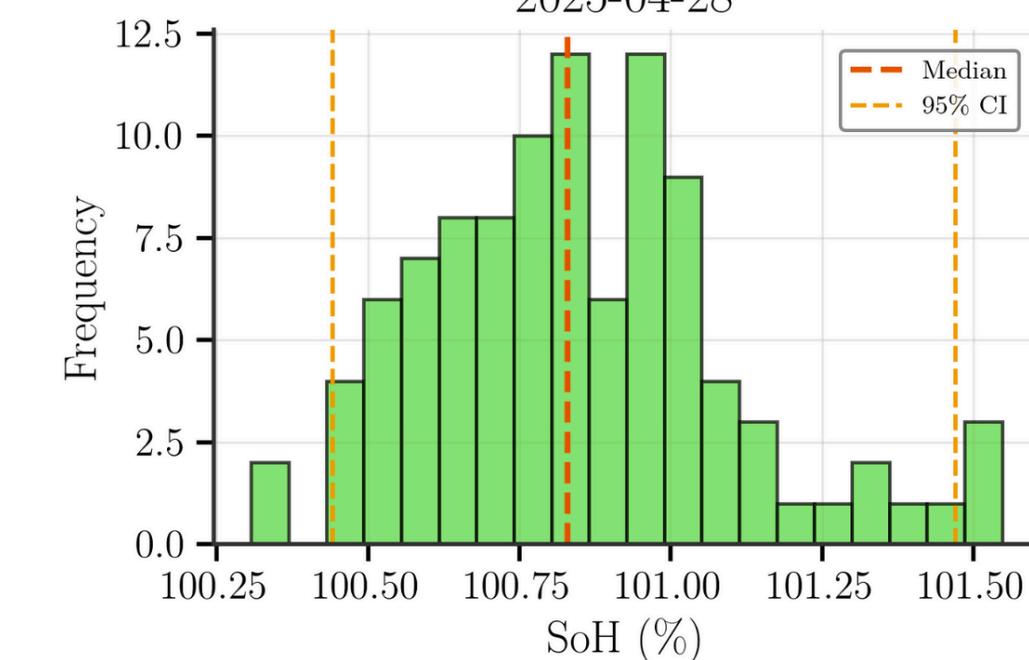
SOH

State of Health (SoH) Model

- Built **on top of the SoC model**
- Accurate SoC estimation
 - → basis for SoH estimation
- Method: OCV curve scaling
- Poor data quality (SoC > 20%)
- Two layers of uncertainty filtering
 - Bootstrapping
 - Kalman filter



Bootstrap Distribution - Window 20
2025-04-28

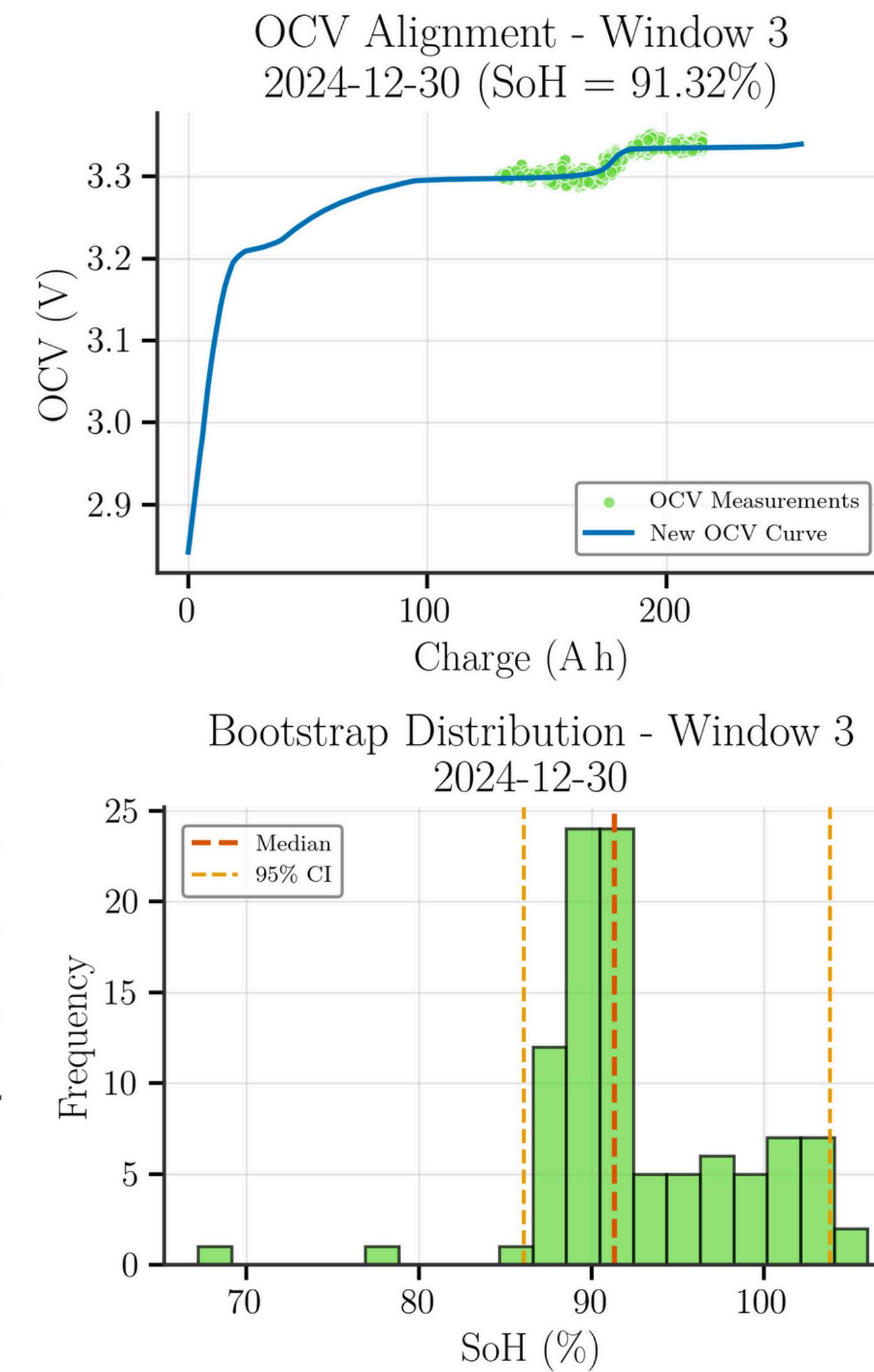
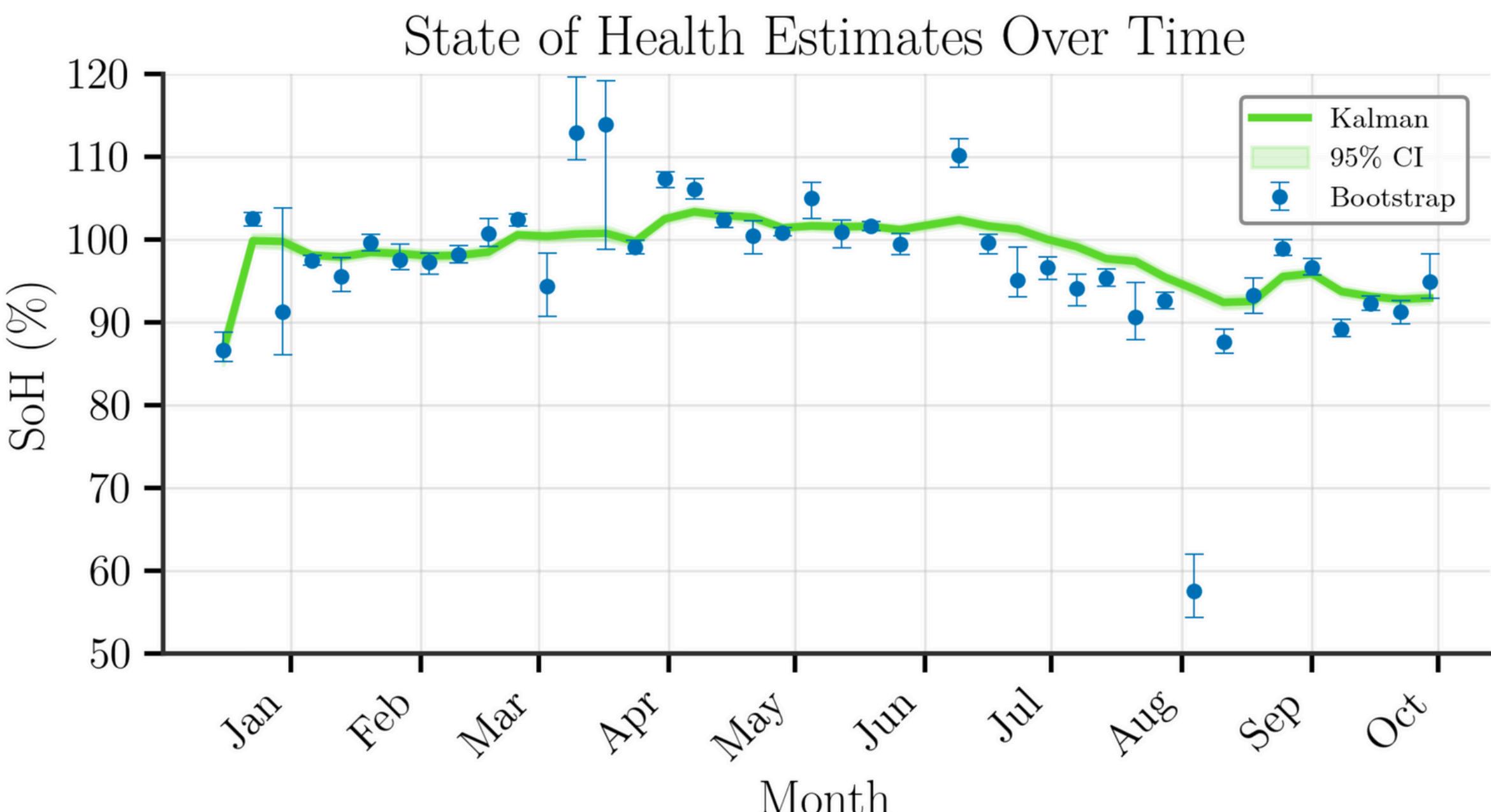




CACTOS

RESULTS: SOH

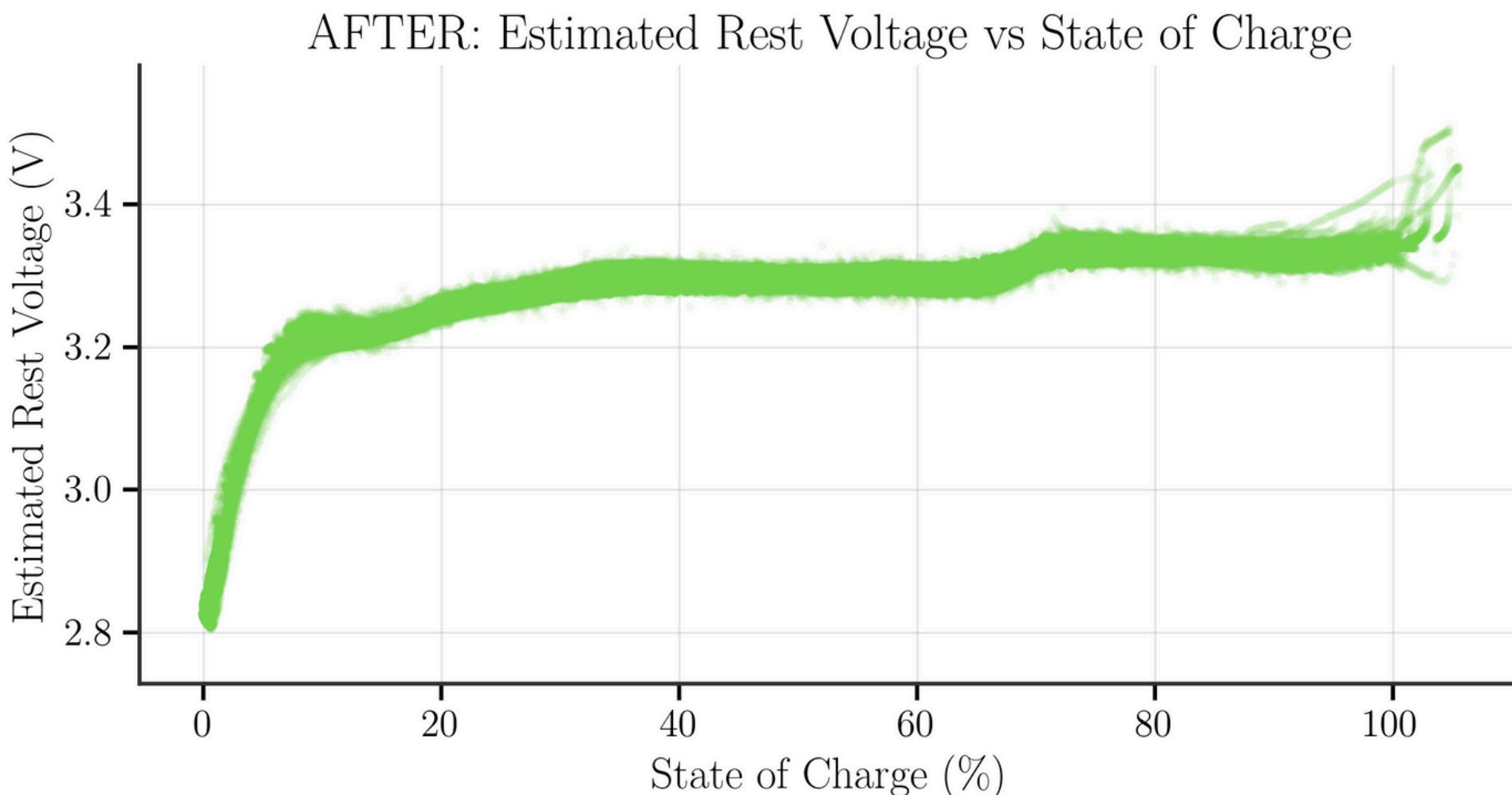
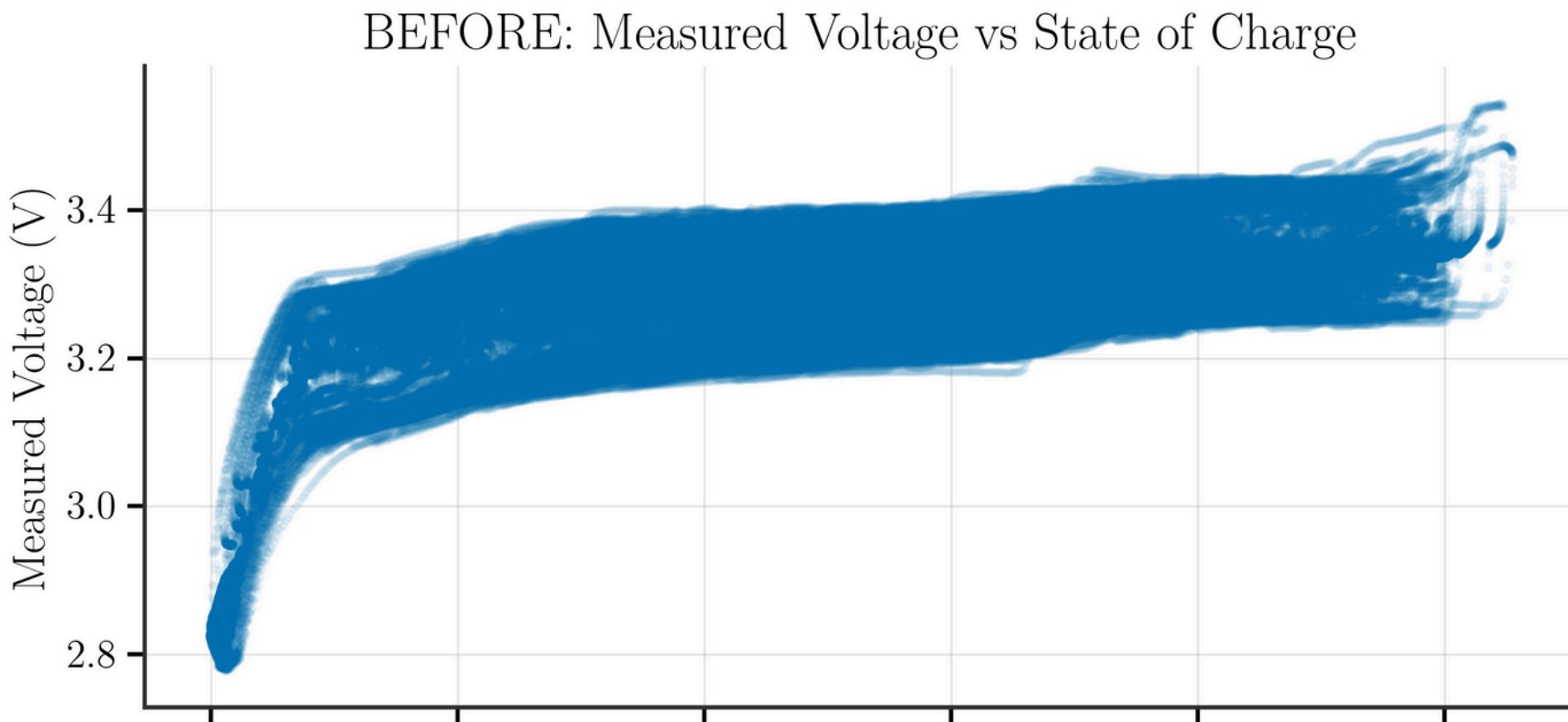
Results: SoH Model





Key Takeaways & Future Research

- Operational data brings challenges
- Data science, domain knowledge, and novel thinking
 - → Accurate SoC model
 - → Insights into the actual dependencies of the cells
 - → Production readiness
- Future research
 - Further SoH model validation
 - Aging dependencies
 - SoH estimates into the SoC model





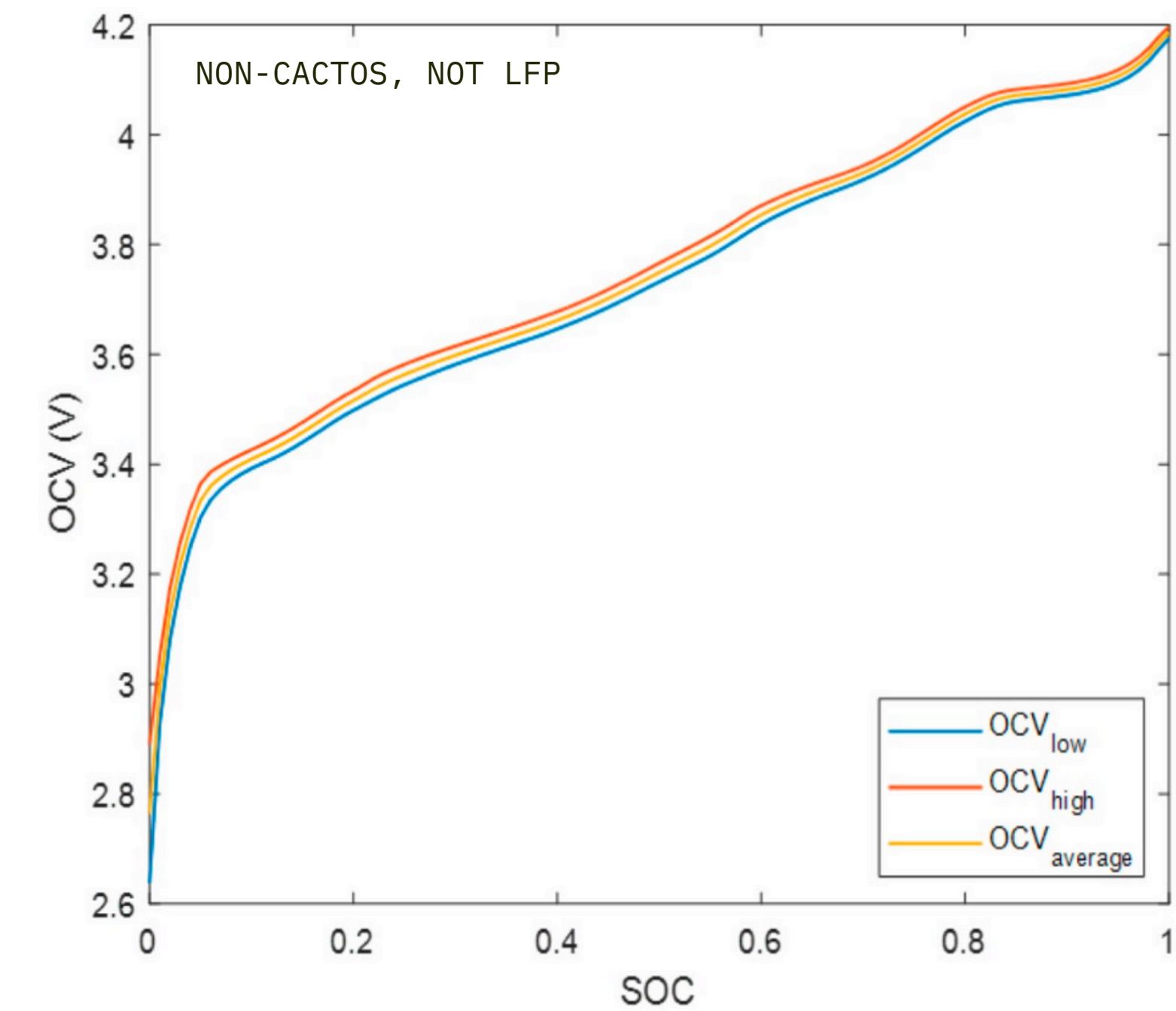
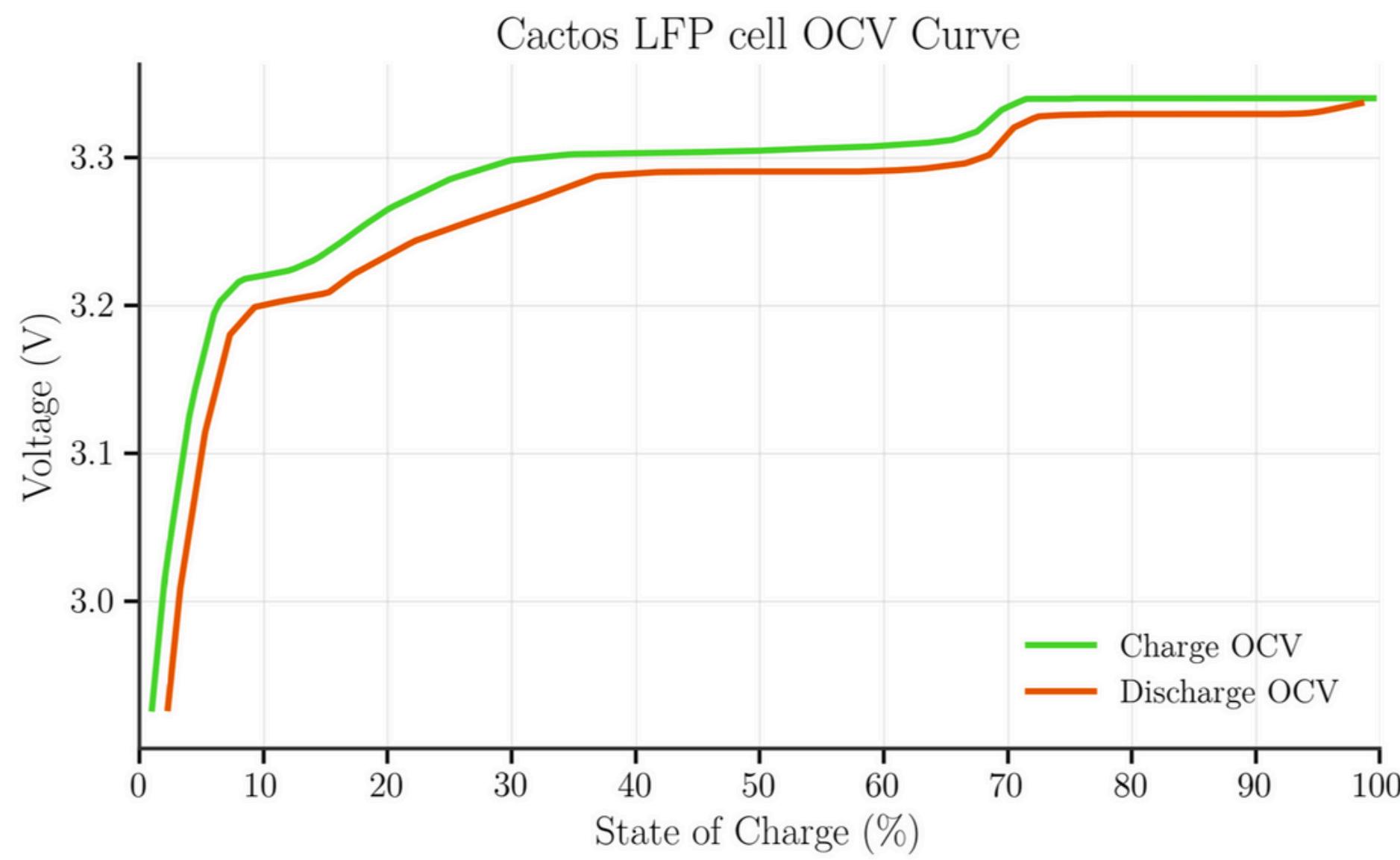
Additional Operational Data Issues

- Measurements not aligned in time
- Voltage calibration bias
- Measurement inaccuracies
 - Cell temperature
- OCV-SoC curve inaccuracy

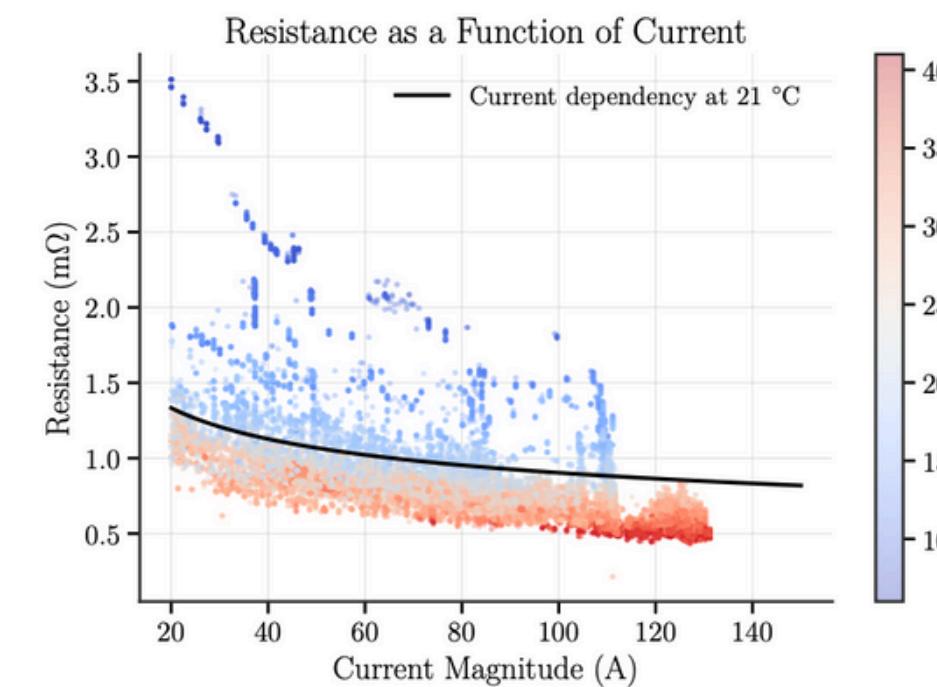
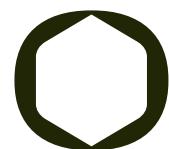


CACTOS

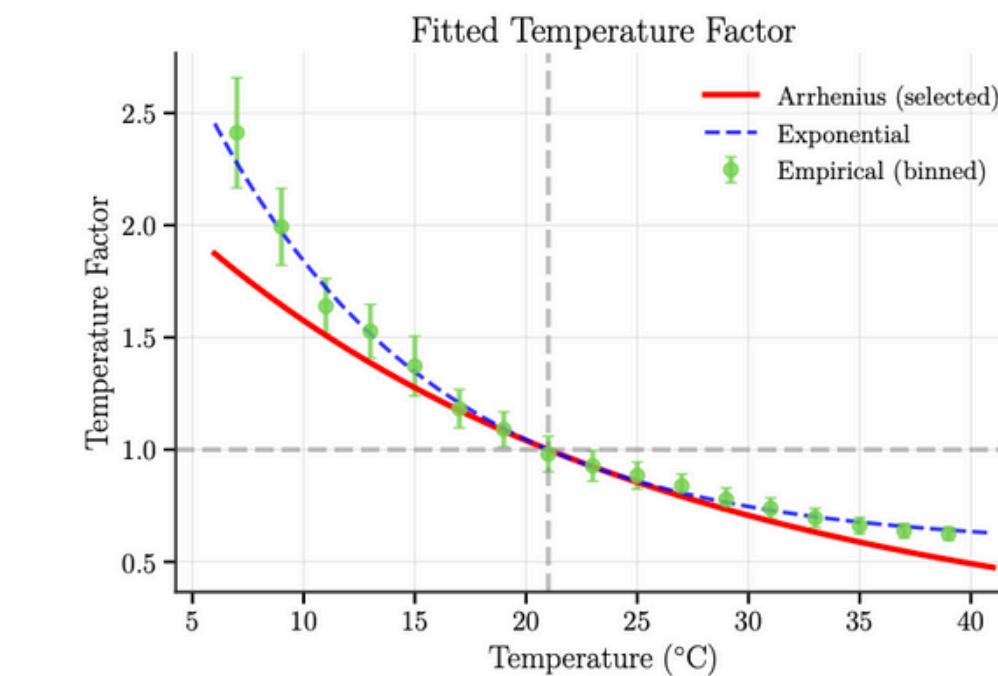
APPENDIX



(b) NMC

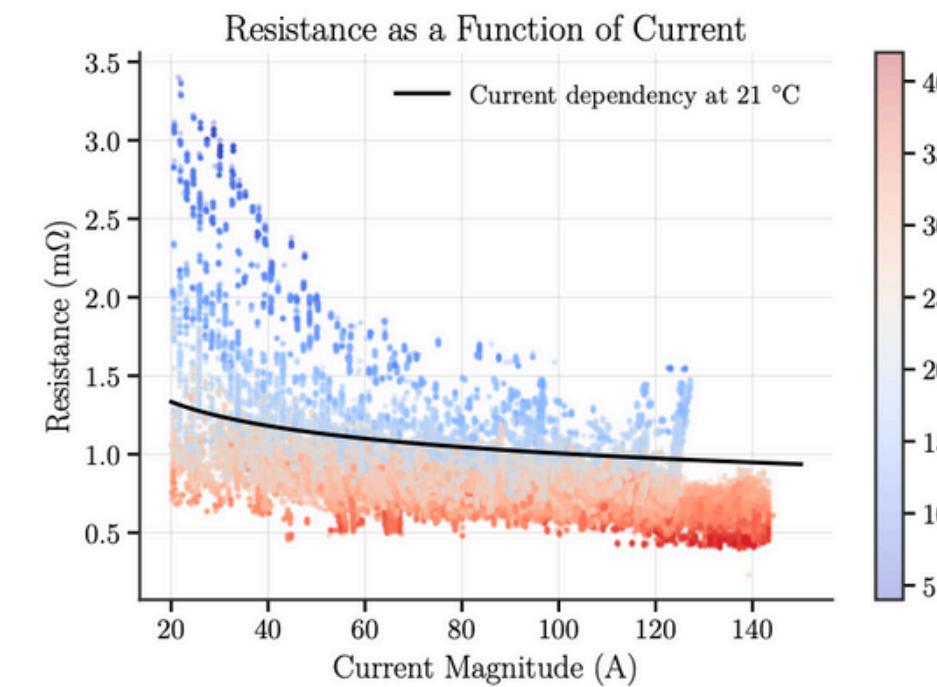


(a) Current dependency of resistance.

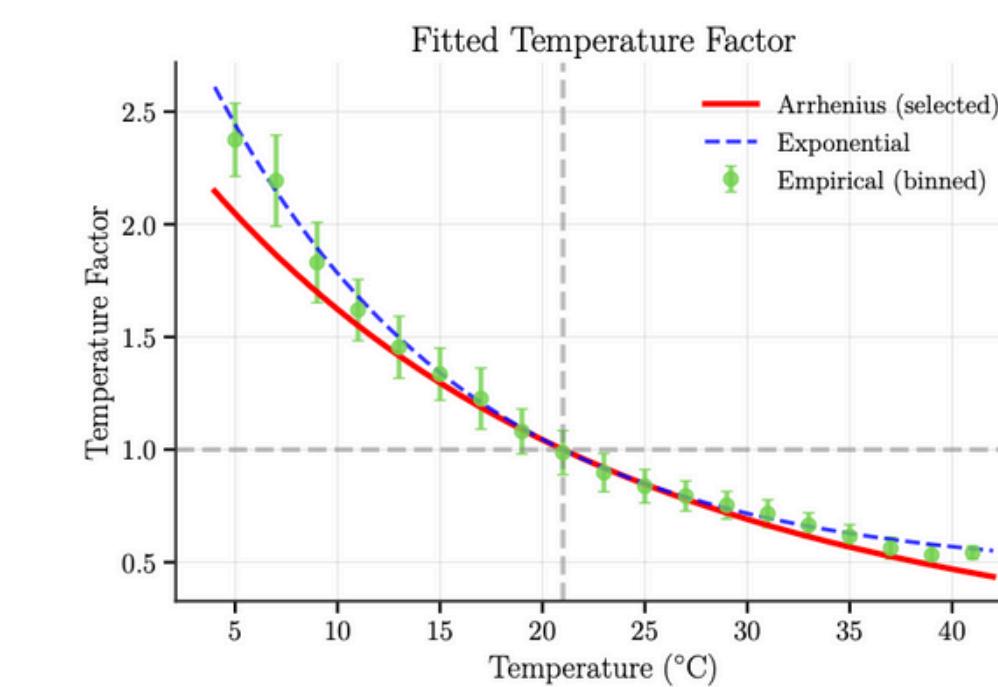


(b) Temperature dependency of resistance.

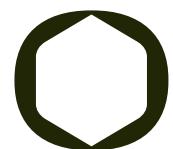
Figure 17: Fitted temperature and current dependencies of resistance for charging.



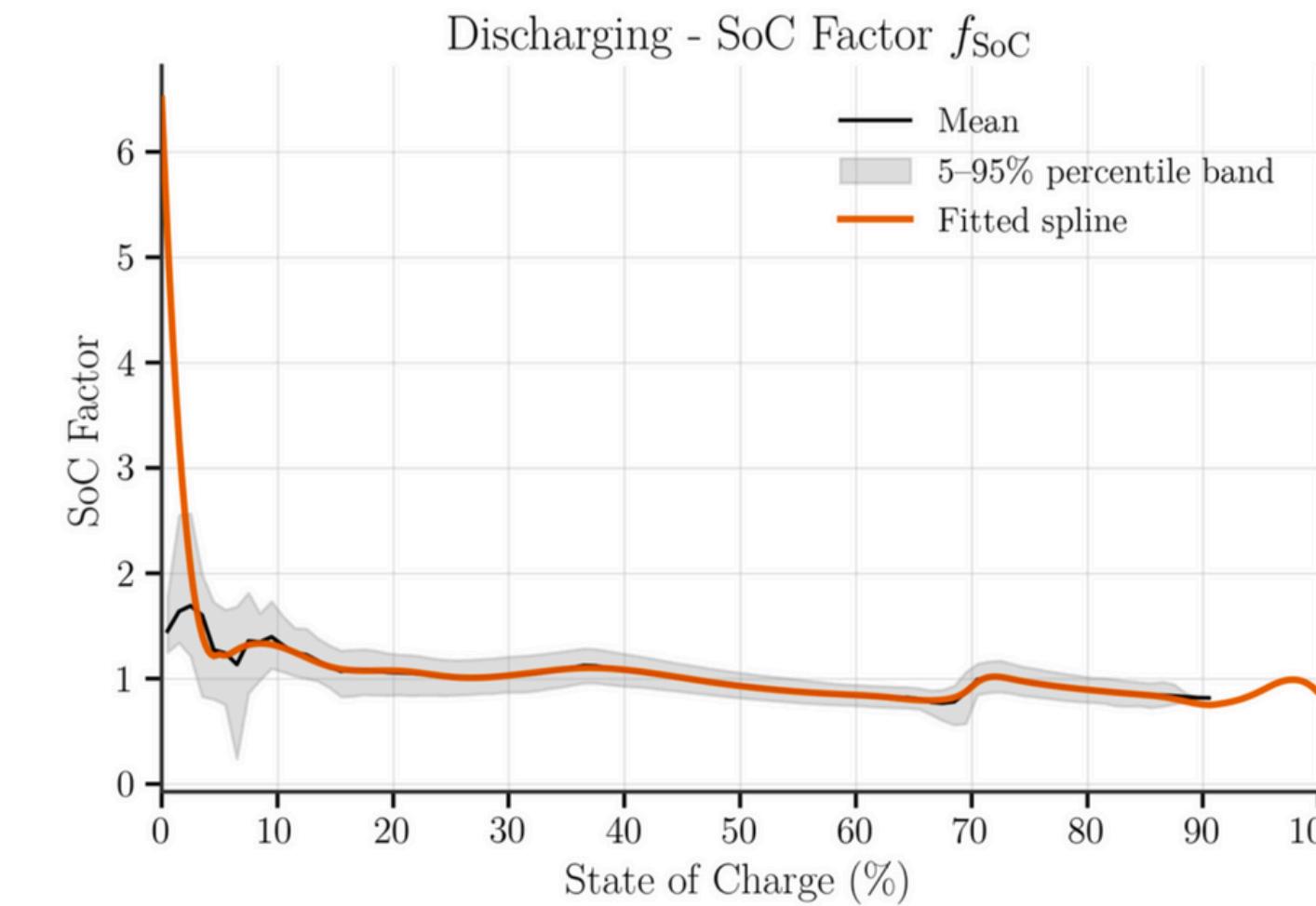
(a) Current dependency of resistance.



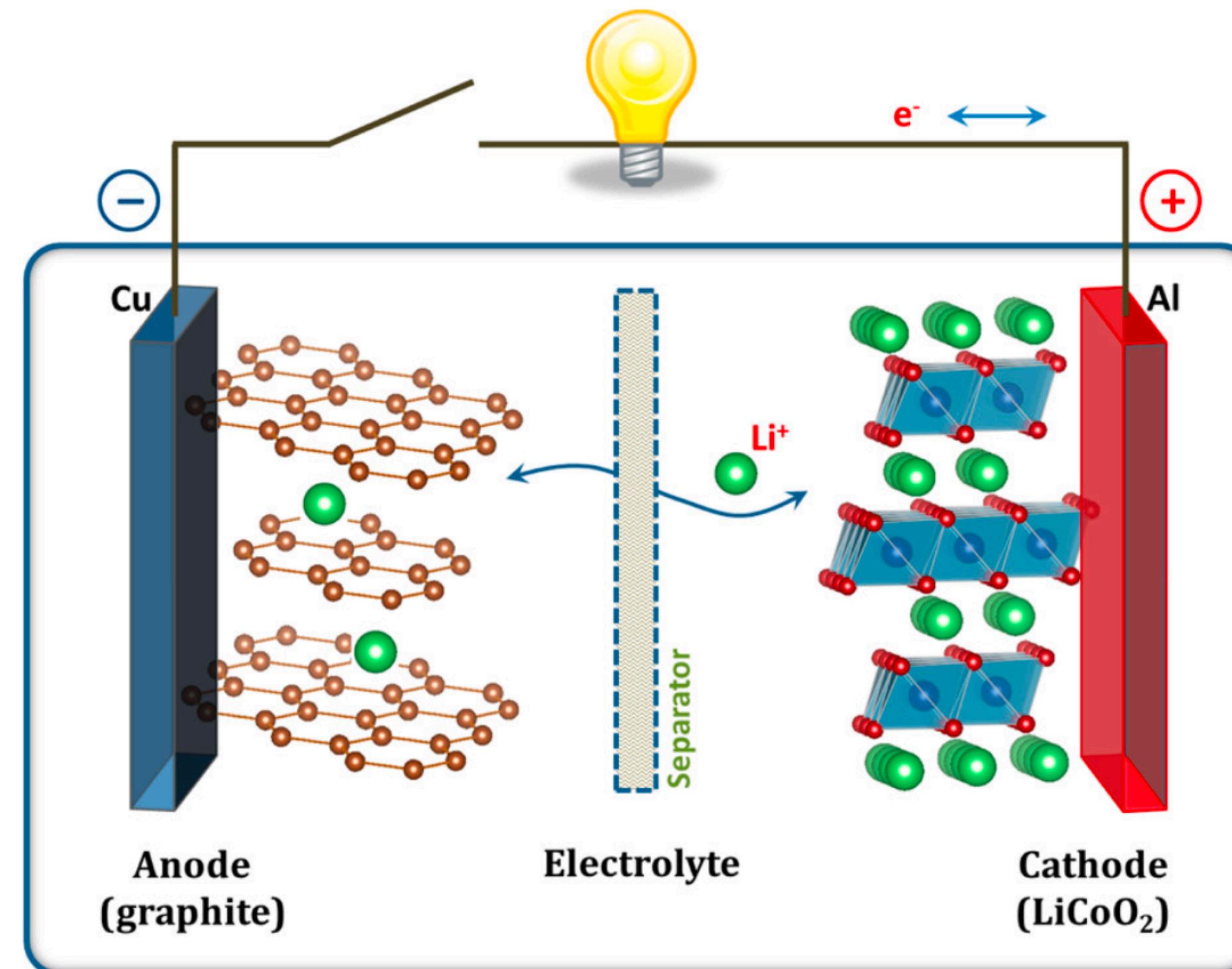
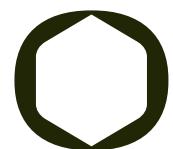
(b) Temperature dependency of resistance.



(a) SoC dependency during charging.

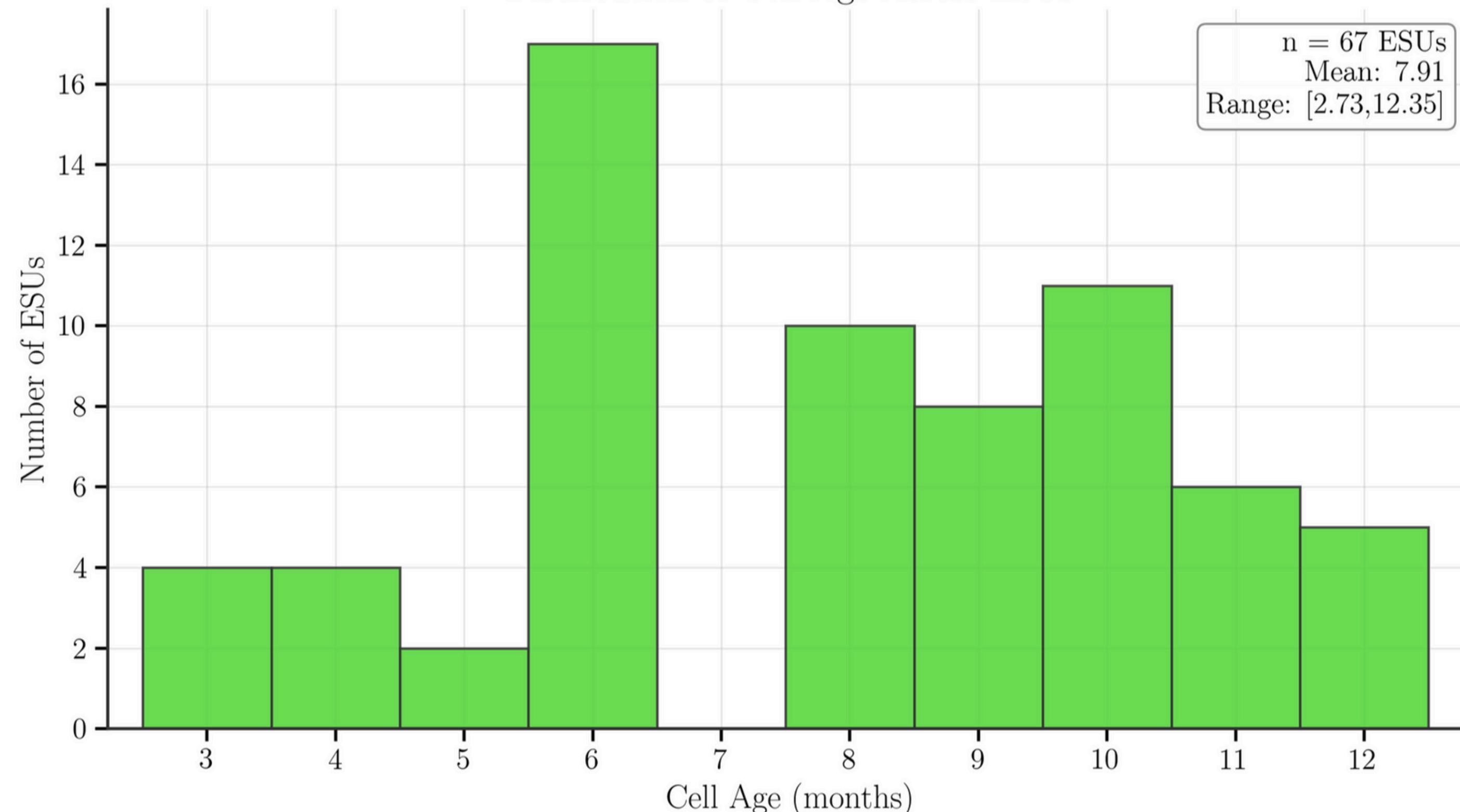


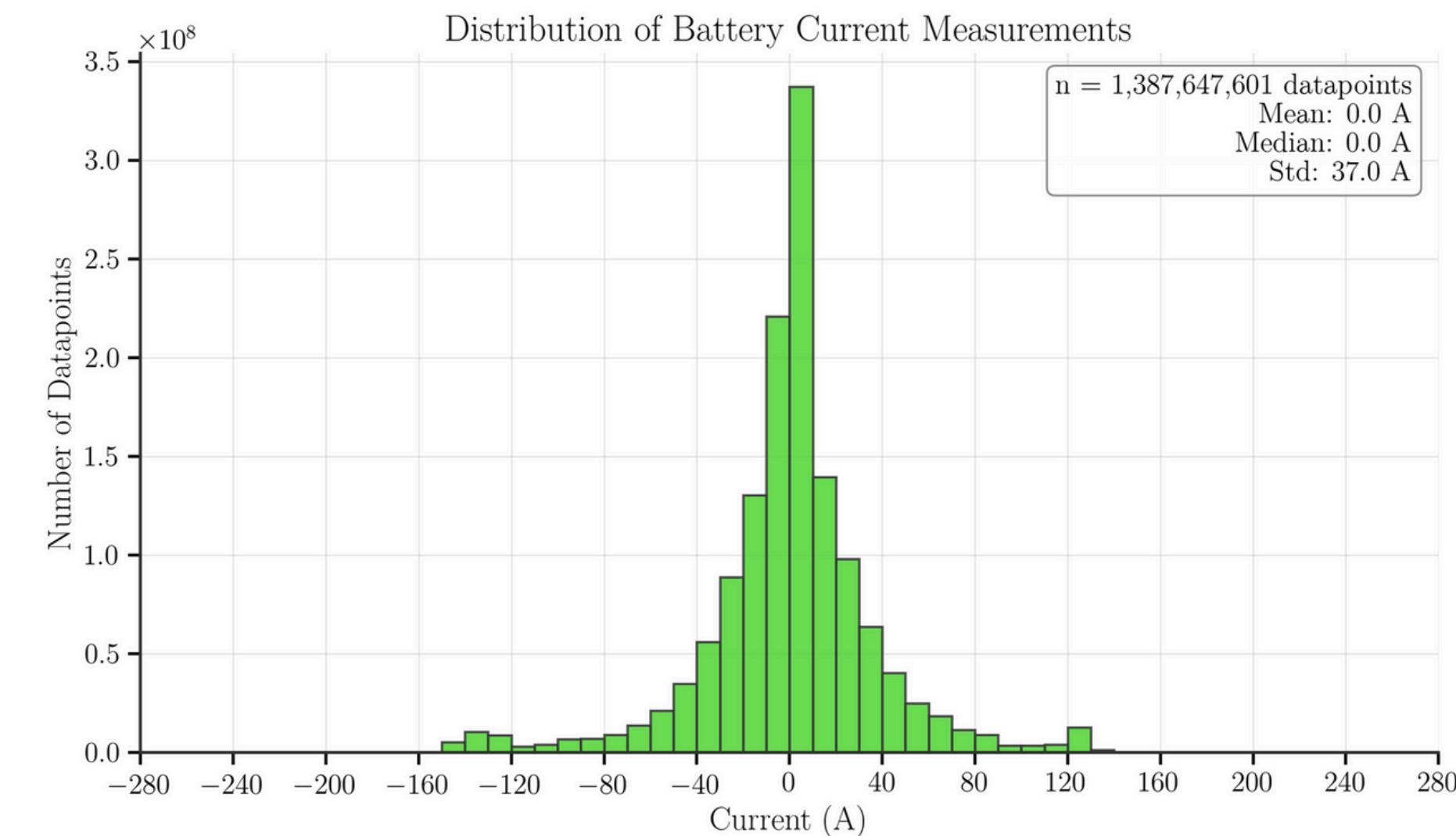
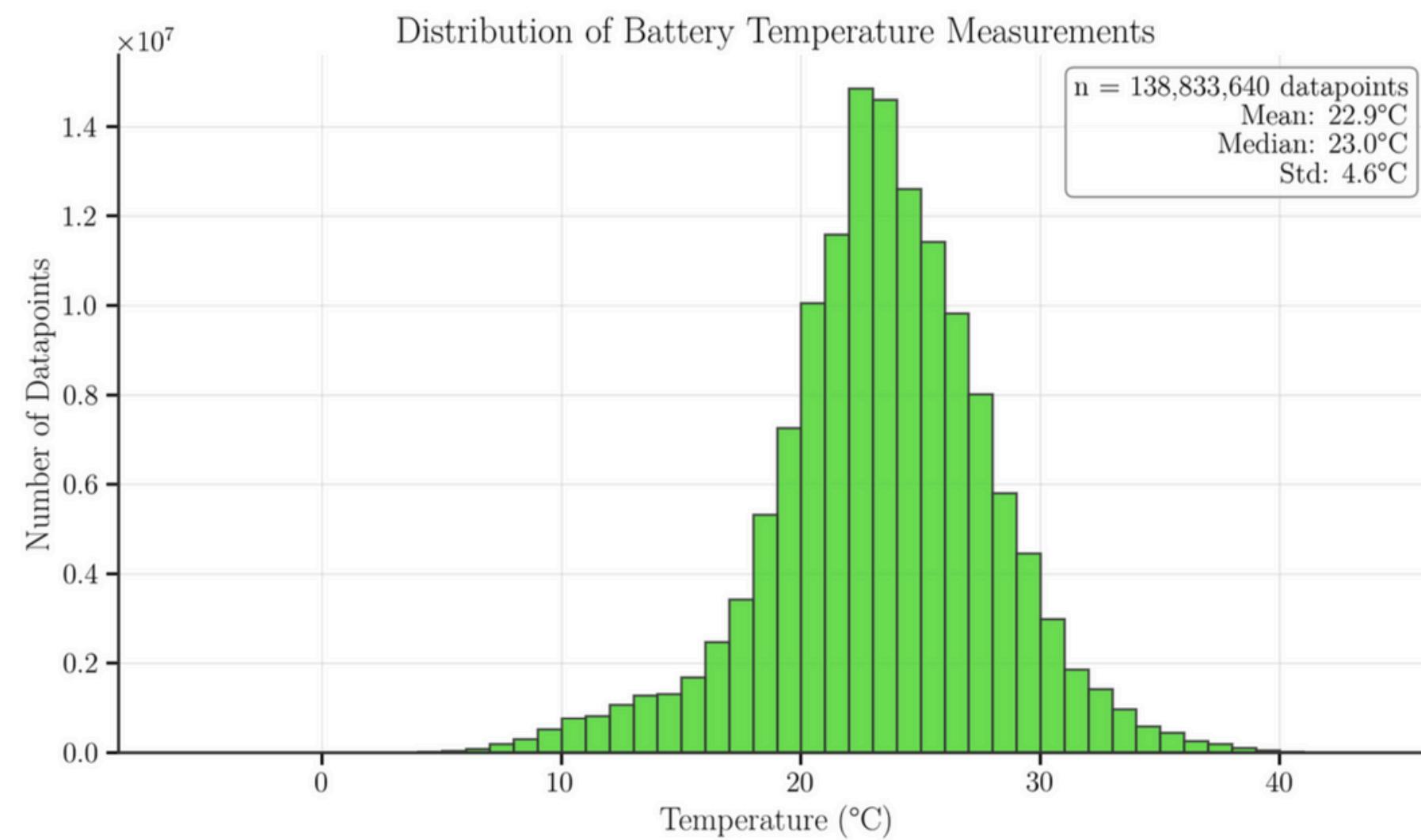
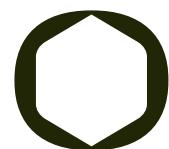
(b) SoC dependency during discharging.

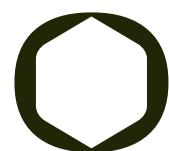




Distribution of Cell Age Across ESUs

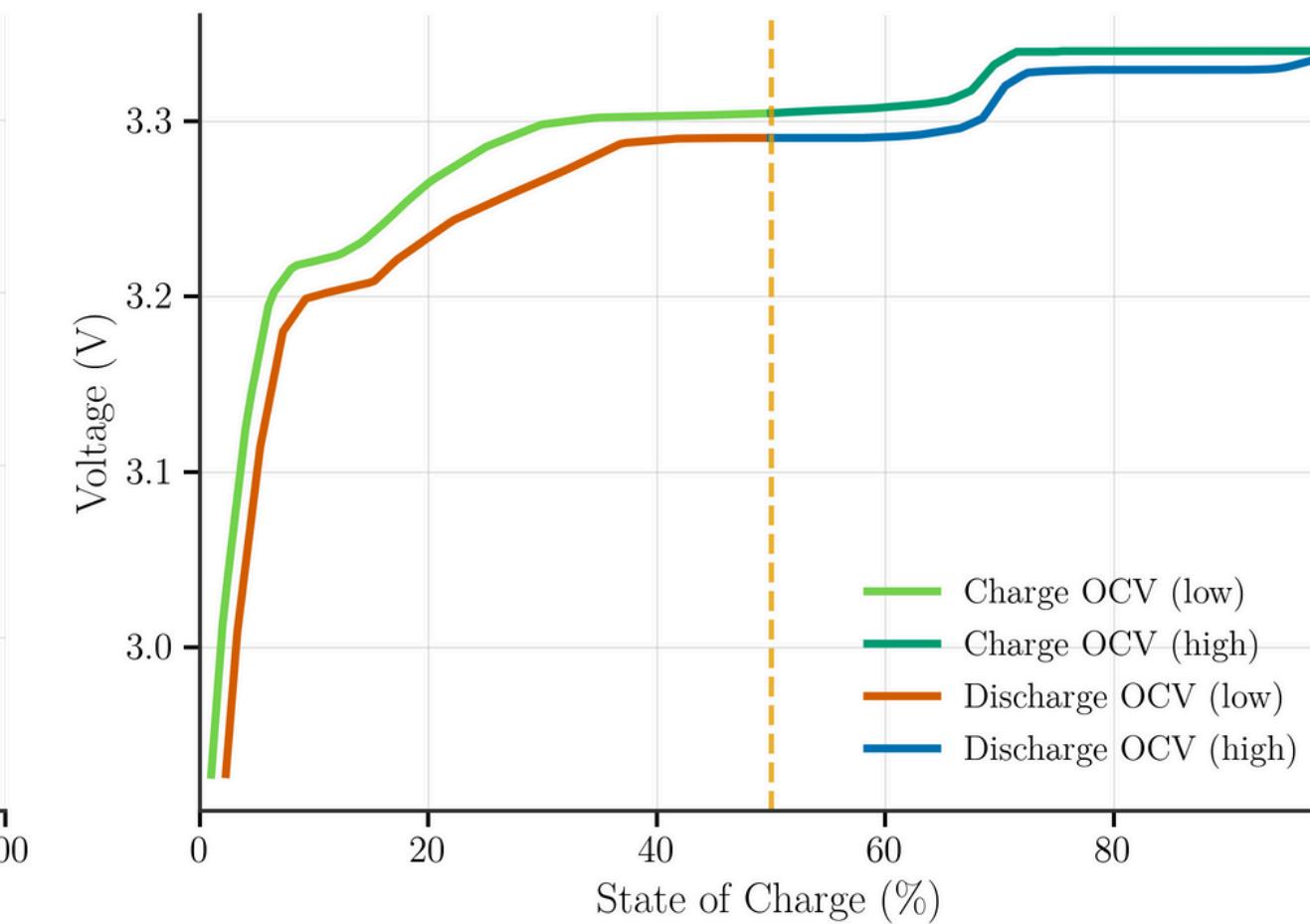
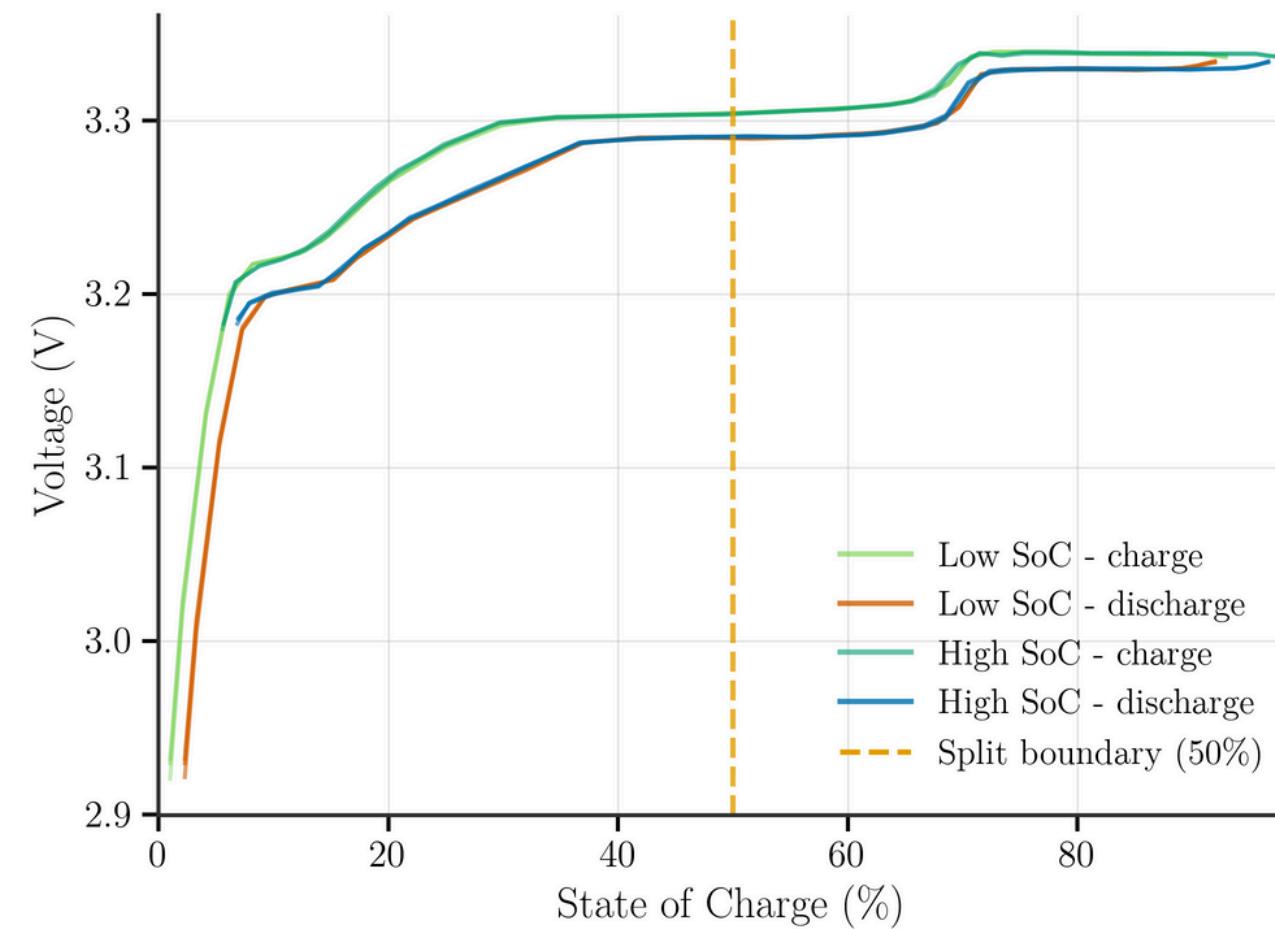
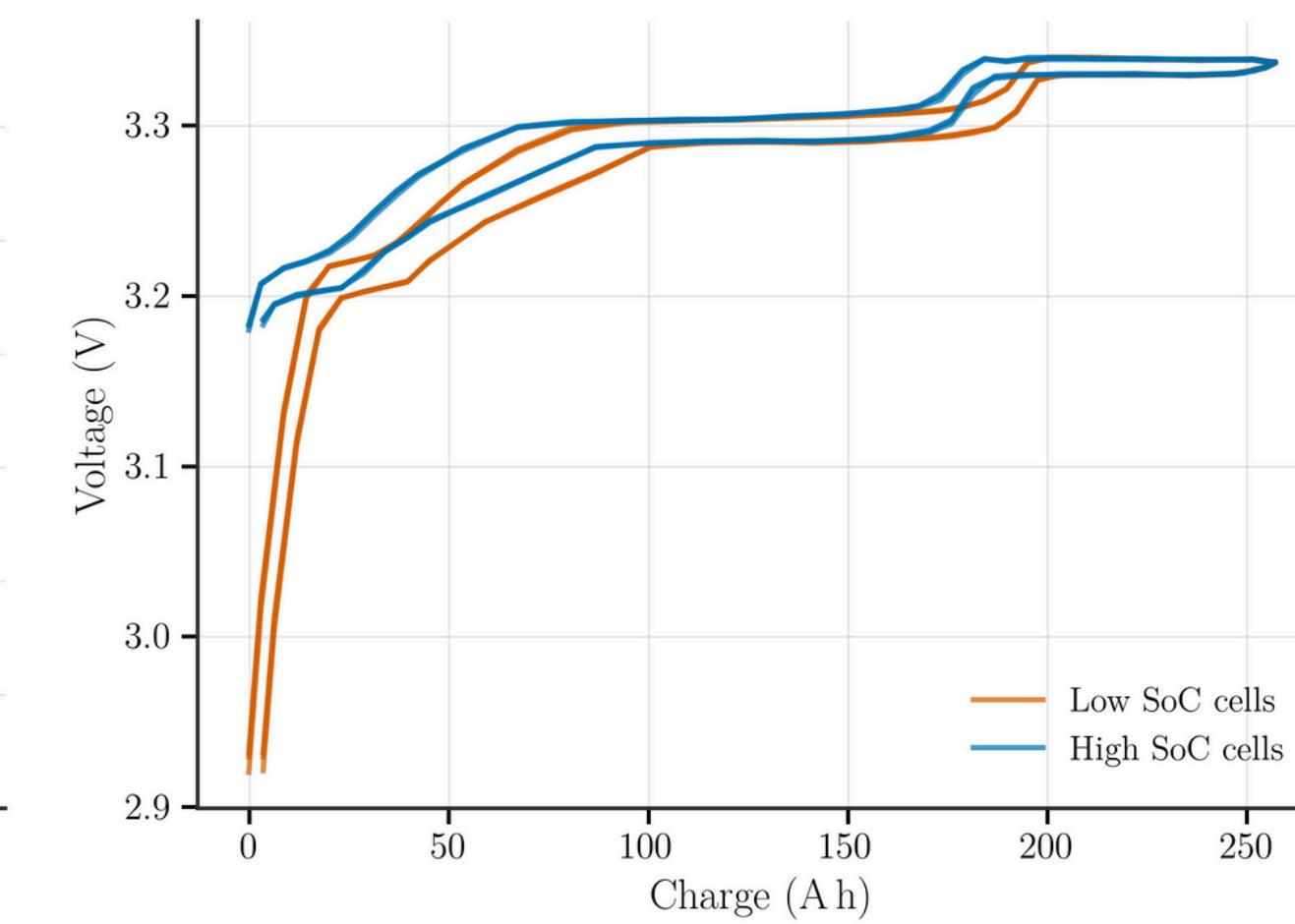
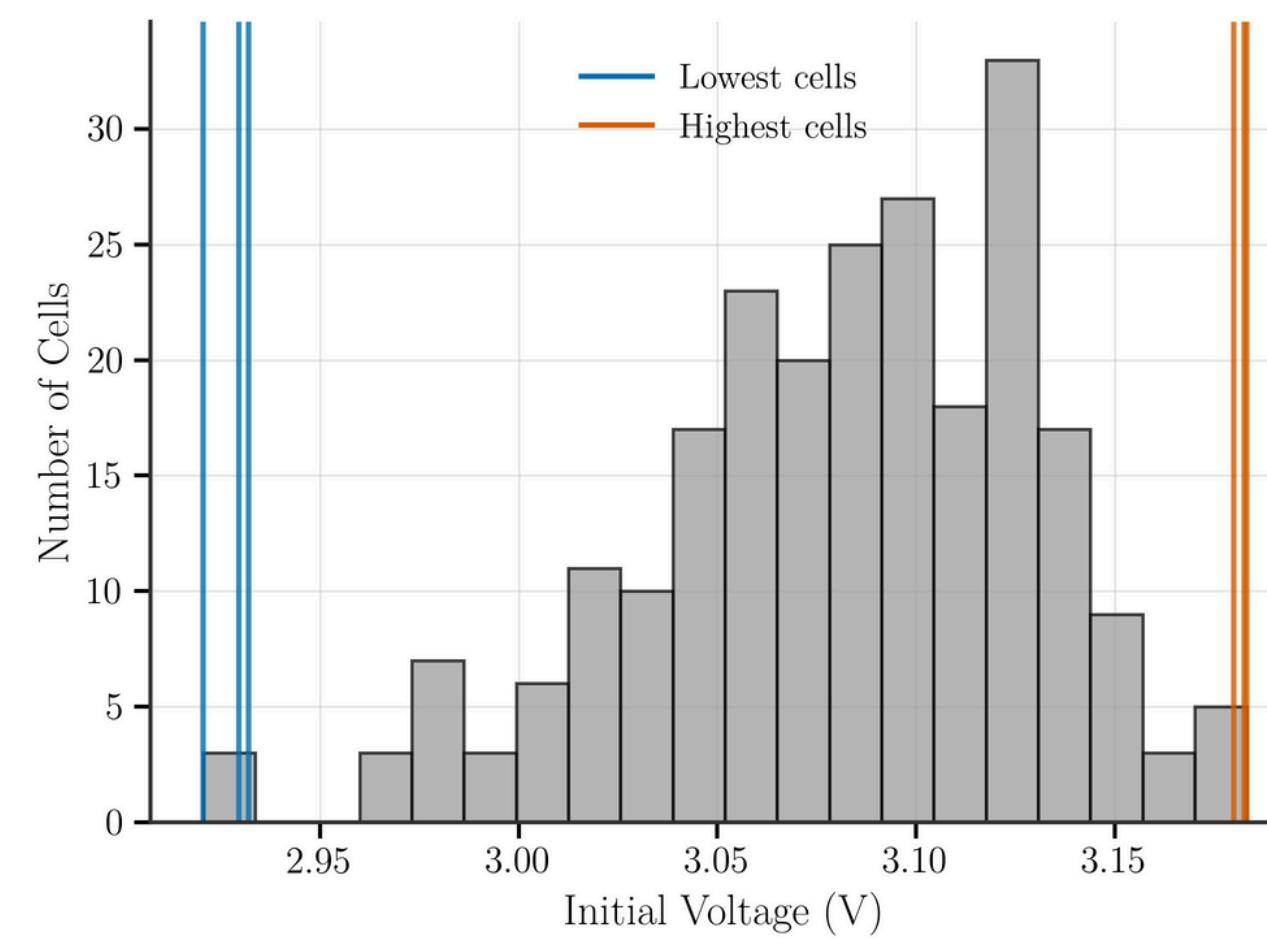


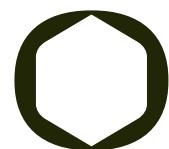




CACTOS

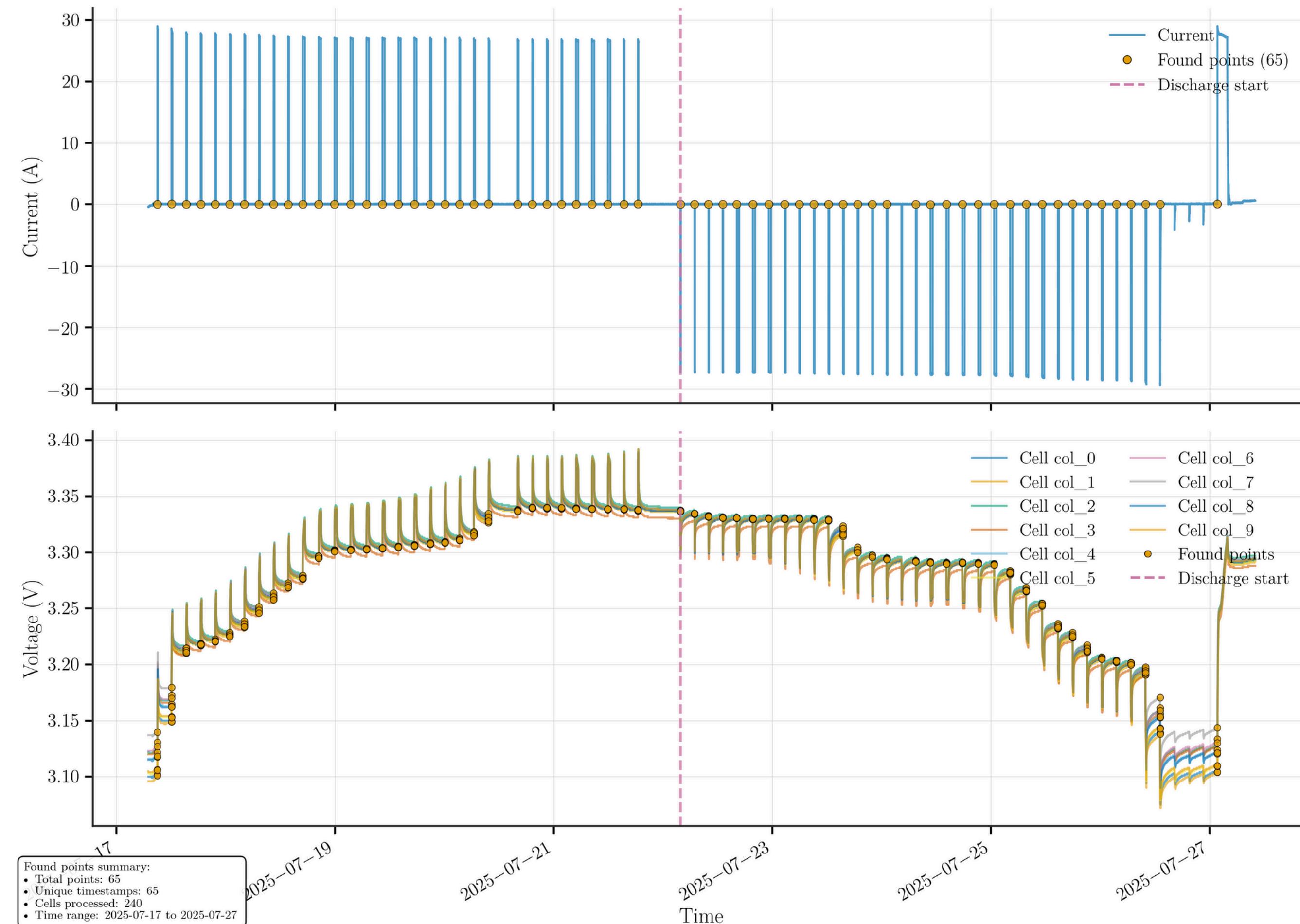
APPENDIX: OCV CURVE

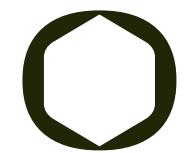




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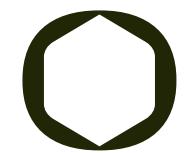
APPENDIX: OCV CURVE





CACTOS

APPENDIX



CACTOS

APPENDIX